

Small- and large-signal modeling of silicon-based substrates

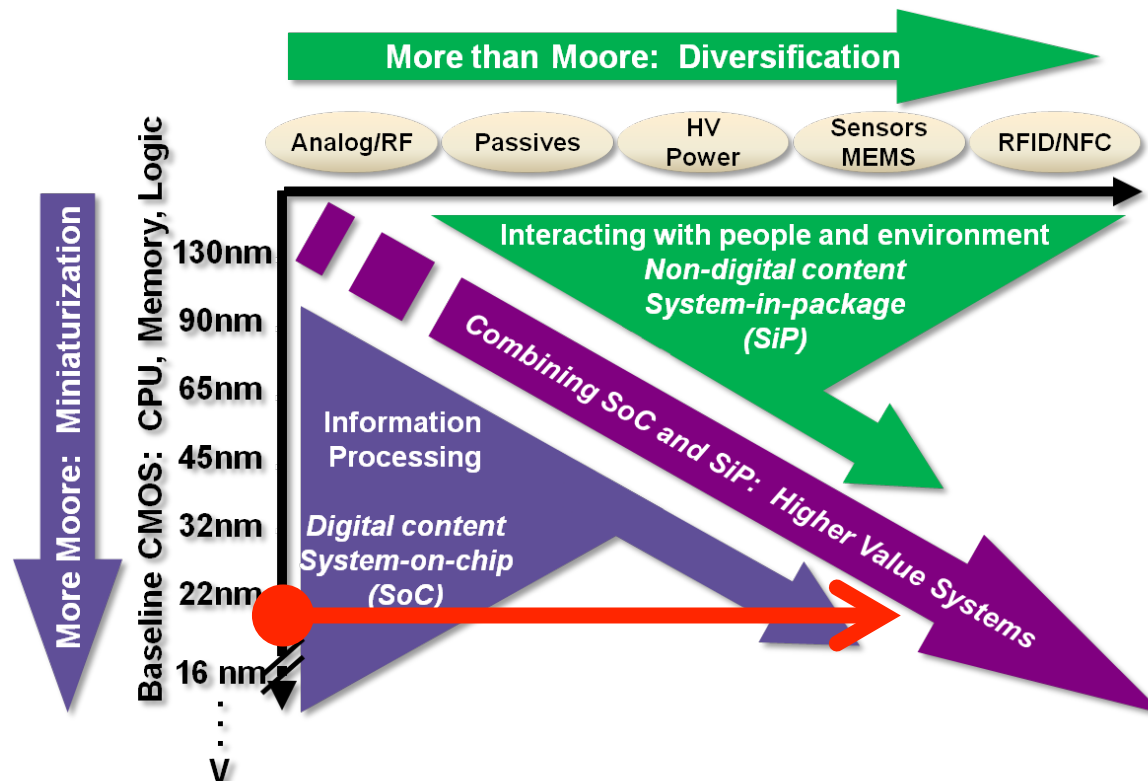
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Content

- Context
- Small-signal modeling
 - Substrate impact
 - Modeling tools + examples of use
- Large-signal modeling
 - Motivation
 - Non-linear signal distortion
 - Modeling approach
 - Carrier dynamics and finite inertia
 - Dips and saturations in HD components
- Conclusions

Context



Context

= Digital chip + RF chip(s) = More process **COST!**



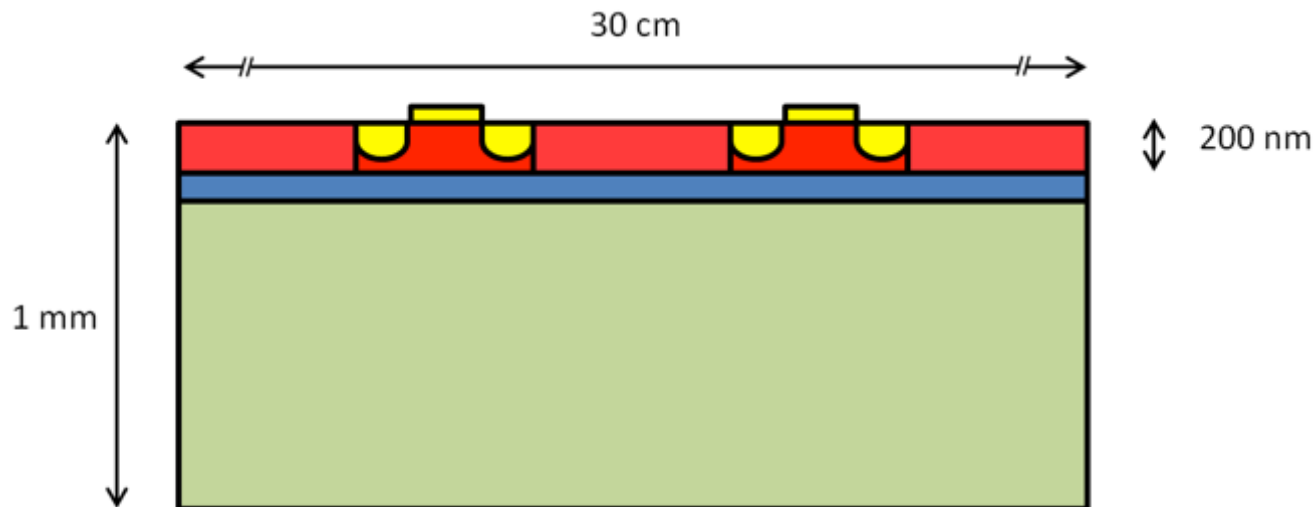
⇒ **Integrate on a single substrate:**

Cost ↘

Performance ↗

Context

- **What is a substrate??**
- For a long time considered solely as a **mechanical support**.

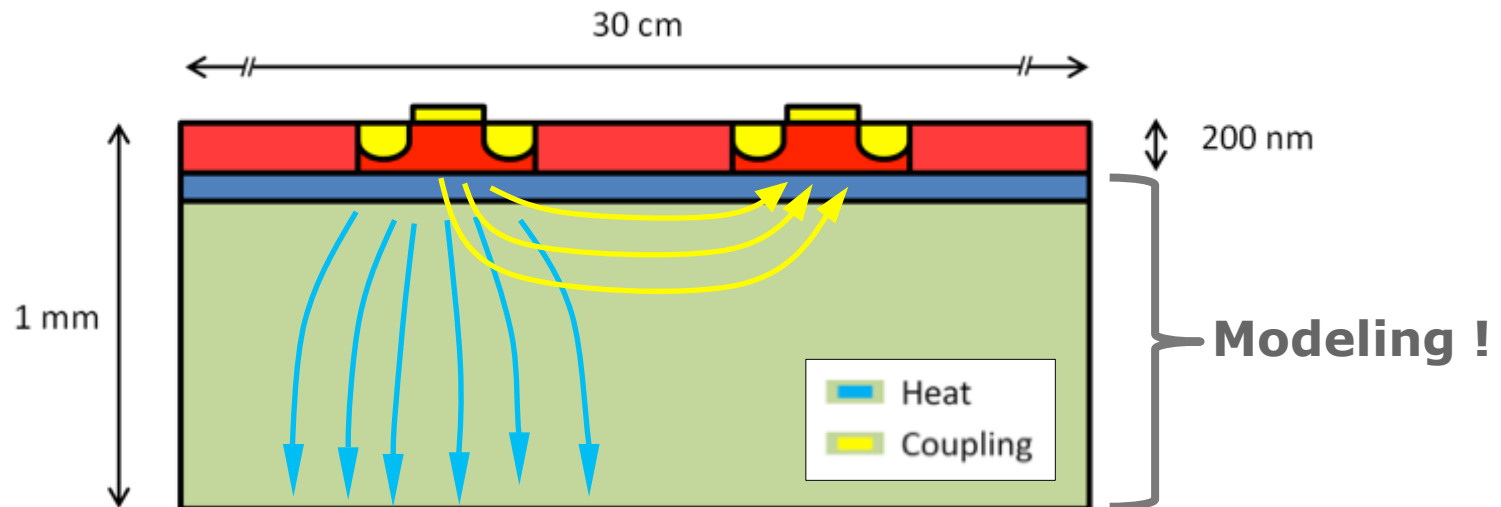


Context

What is a substrate??

Now however this mechanical support must provide:

- Thermal evacuation
- Low loss
- Low coupling
- Linearity



Modeling tools

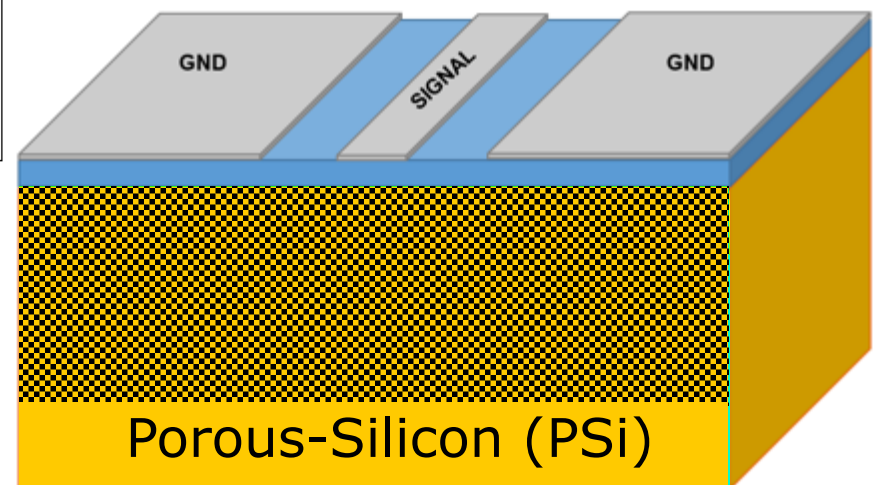
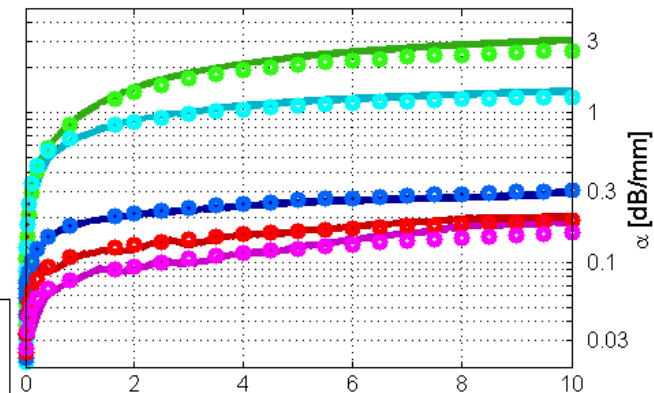
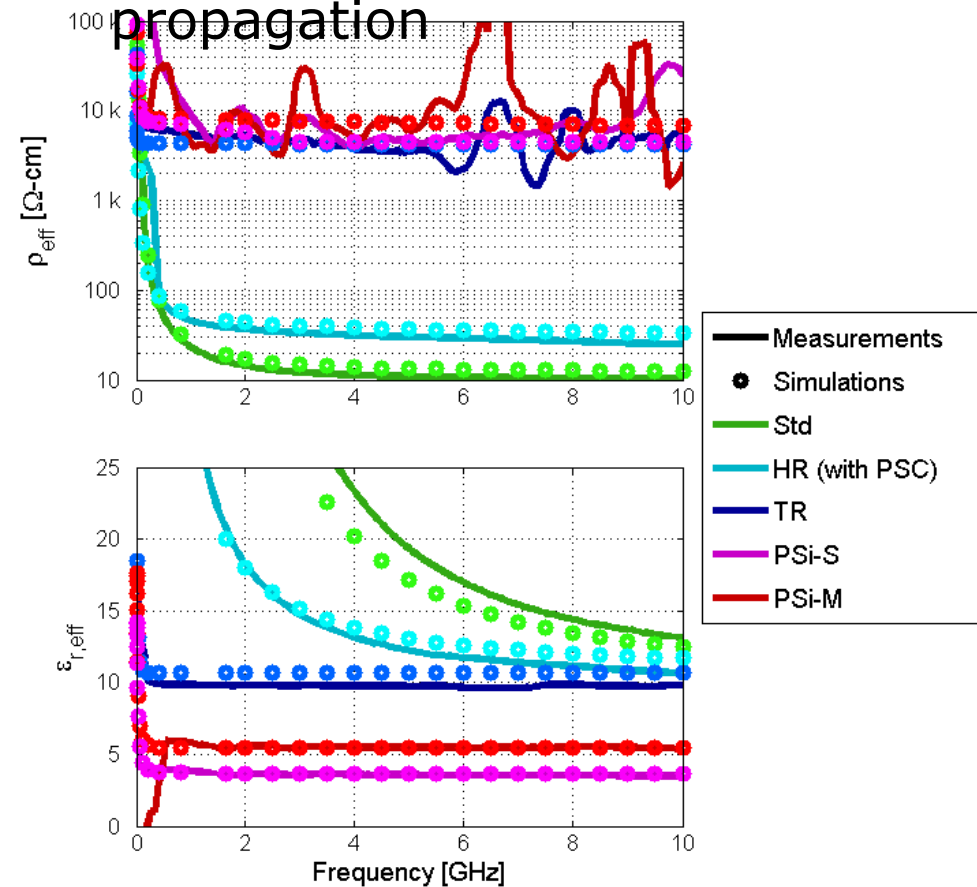
Method	Equations	Speed	Comment	Usability
FEM Device physics (Silvaco, Synopsys,...)	Transport equations (semiconductor)	Very slow	Non-linear capabilities Not propagation	
FEM Full-wave (HFSS,...)	Maxwell	slow	Purely linear Propagation Substrate inhomogeneity difficult to incorporate	
MOM (BEM) (ADS momentum, ...)		Fast		PDK ready
FDM	Kirchhoff	Very fast	Discrete lumped Not propagation	PDK ready
Hybrid			Purely linear MOM+MOM MOM+FEM	PDK ready

Substrate impact:

CPW lines

Small-signal modeling : FEM transport equations + closed form expressions of CPW

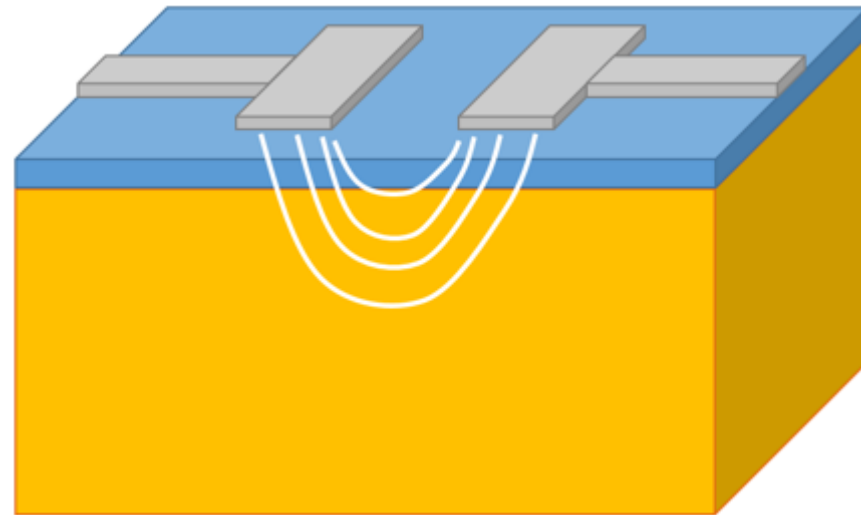
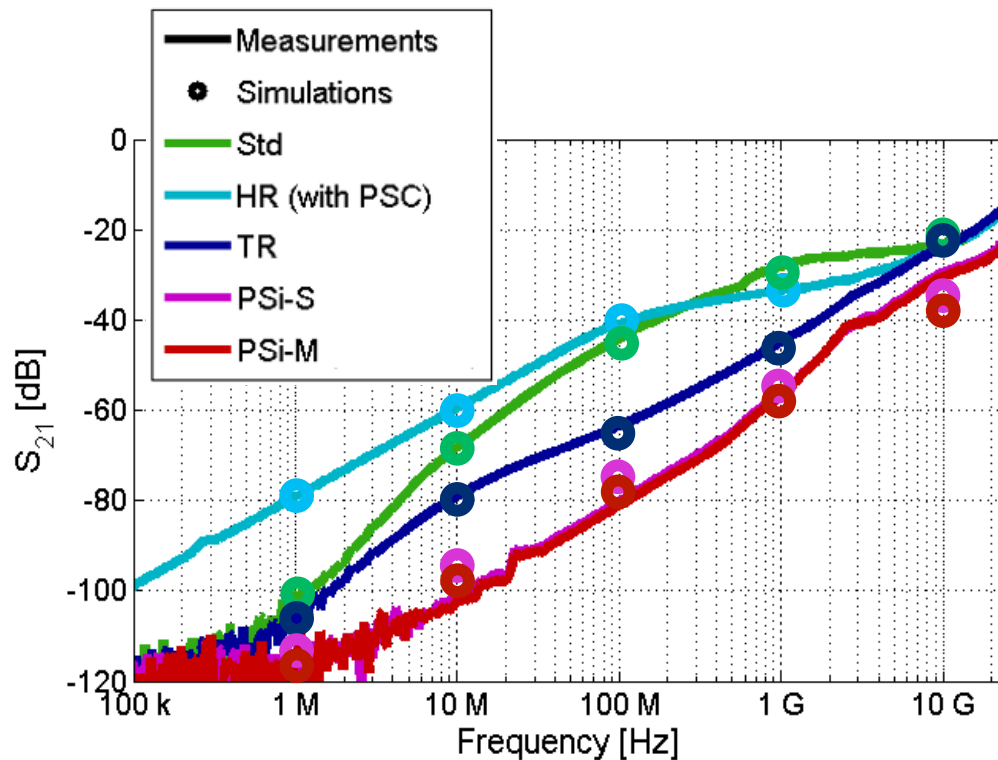
propagation



Substrate impact:

Crosstalk

Small-signal modeling : FEM transport equations

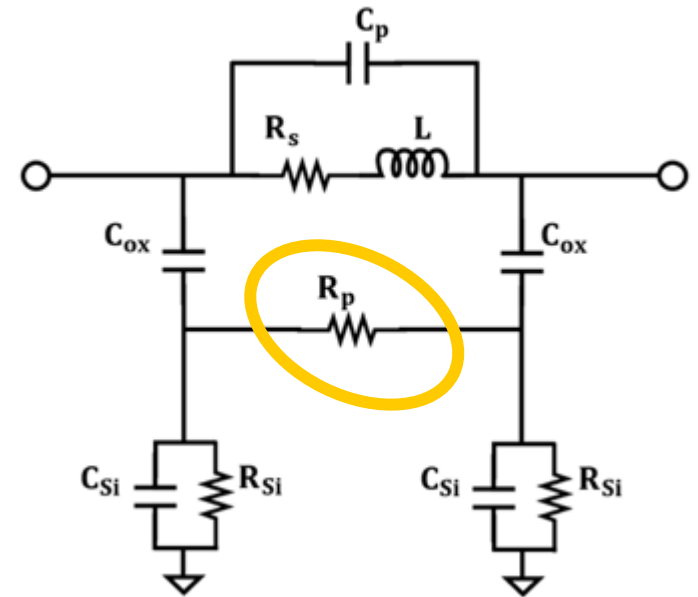
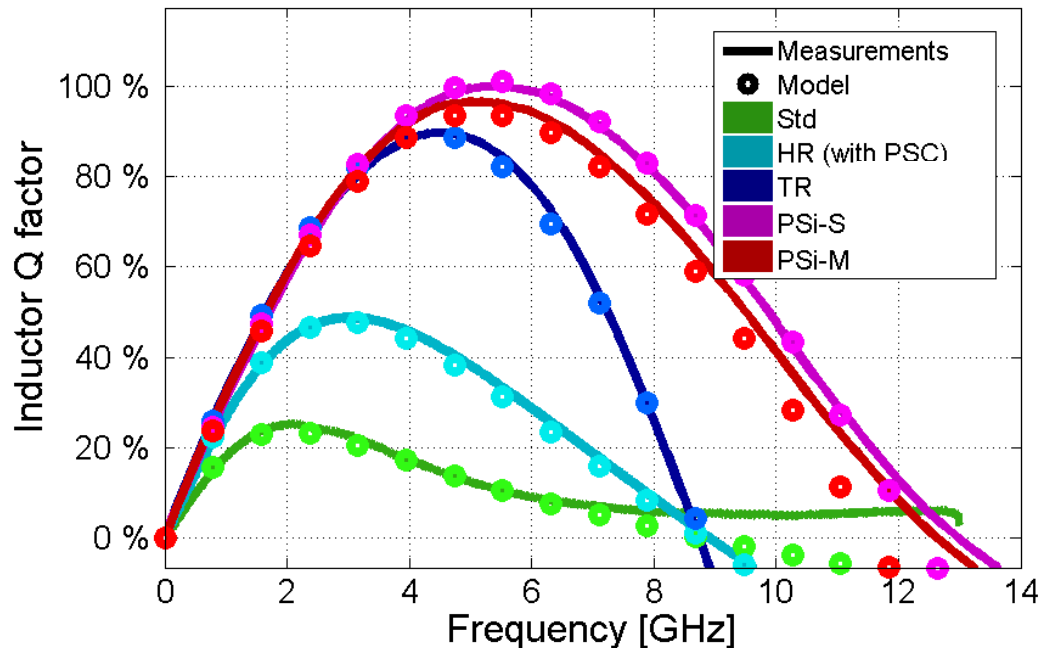


Substrate impact:

Inductor quality

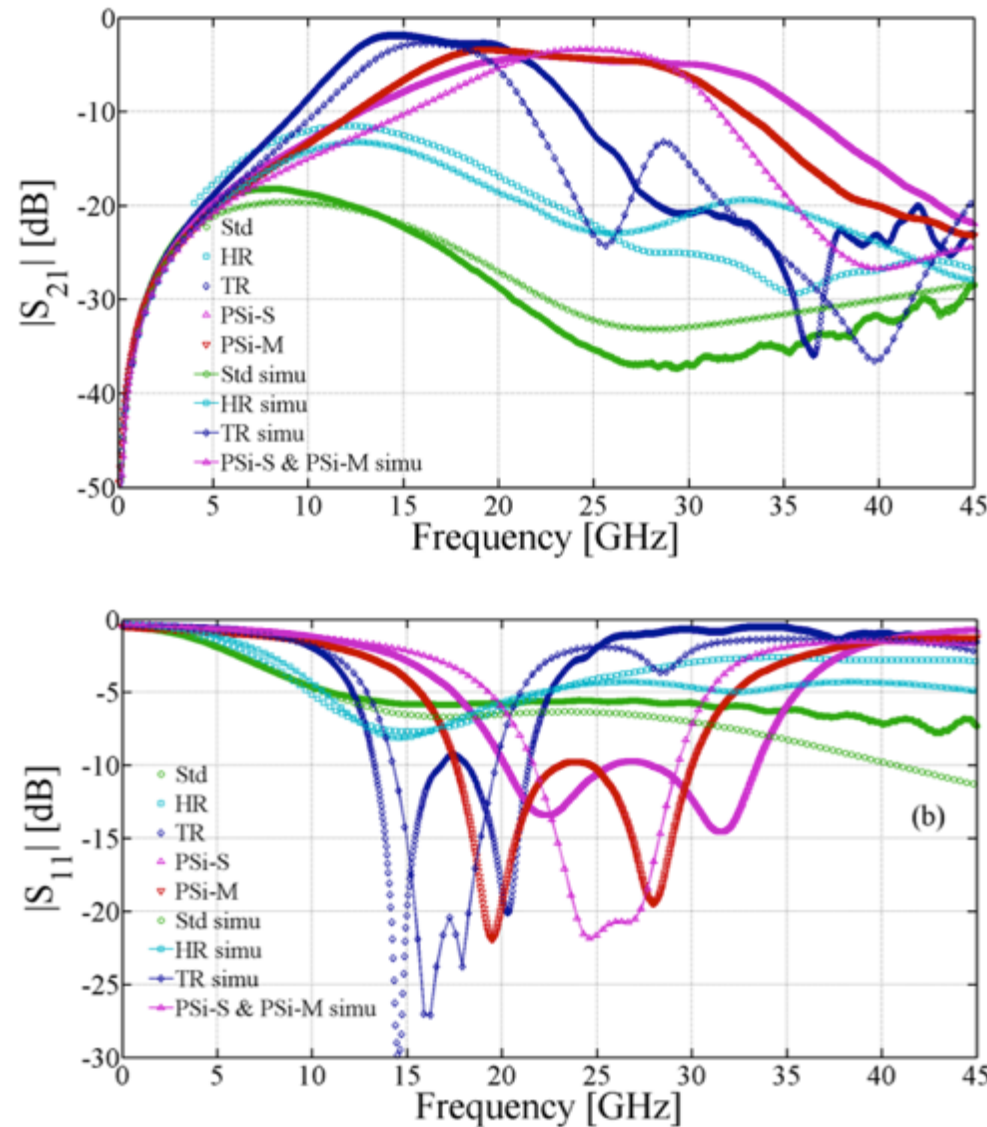
Small-signal modeling :

MOM modeling (inhomogeneous substrate profile from FEM transport equations)



Substrate impact:

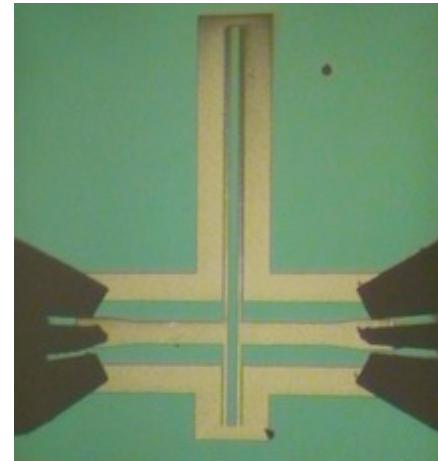
Bandpass filter



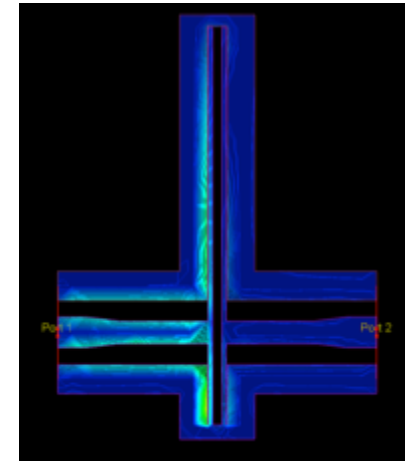
Small-signal modeling:

MOM modeling (inhomogeneous substrate profile from FEM transport equations)

Measurements

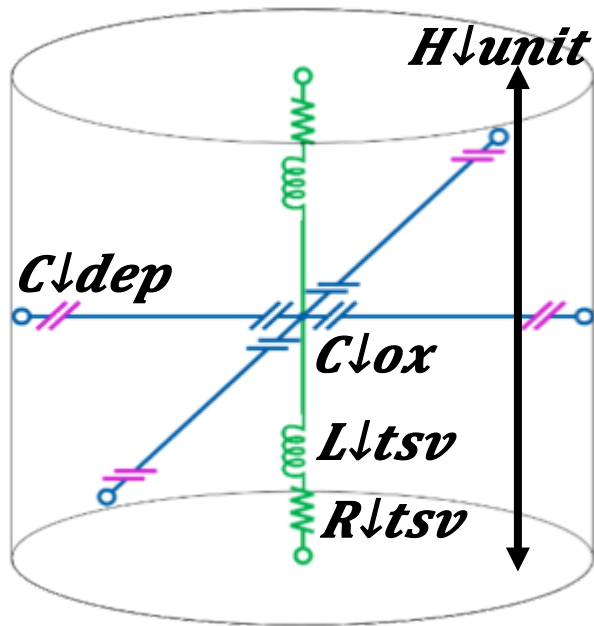


MOM

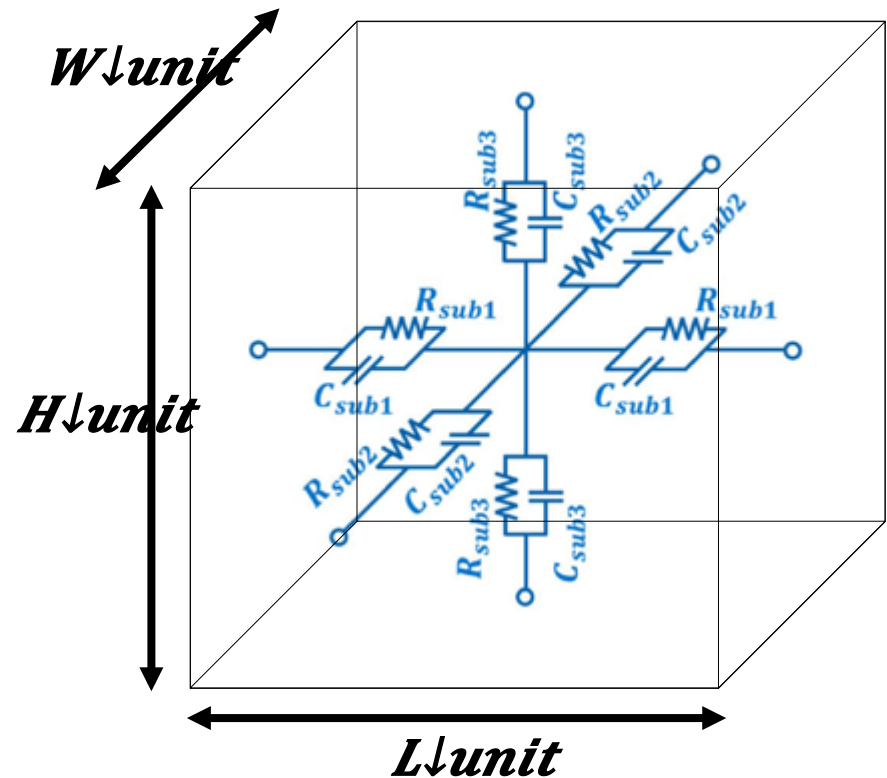


FDM modeling example: **Coupling in 3DICs**

TSV unit cell

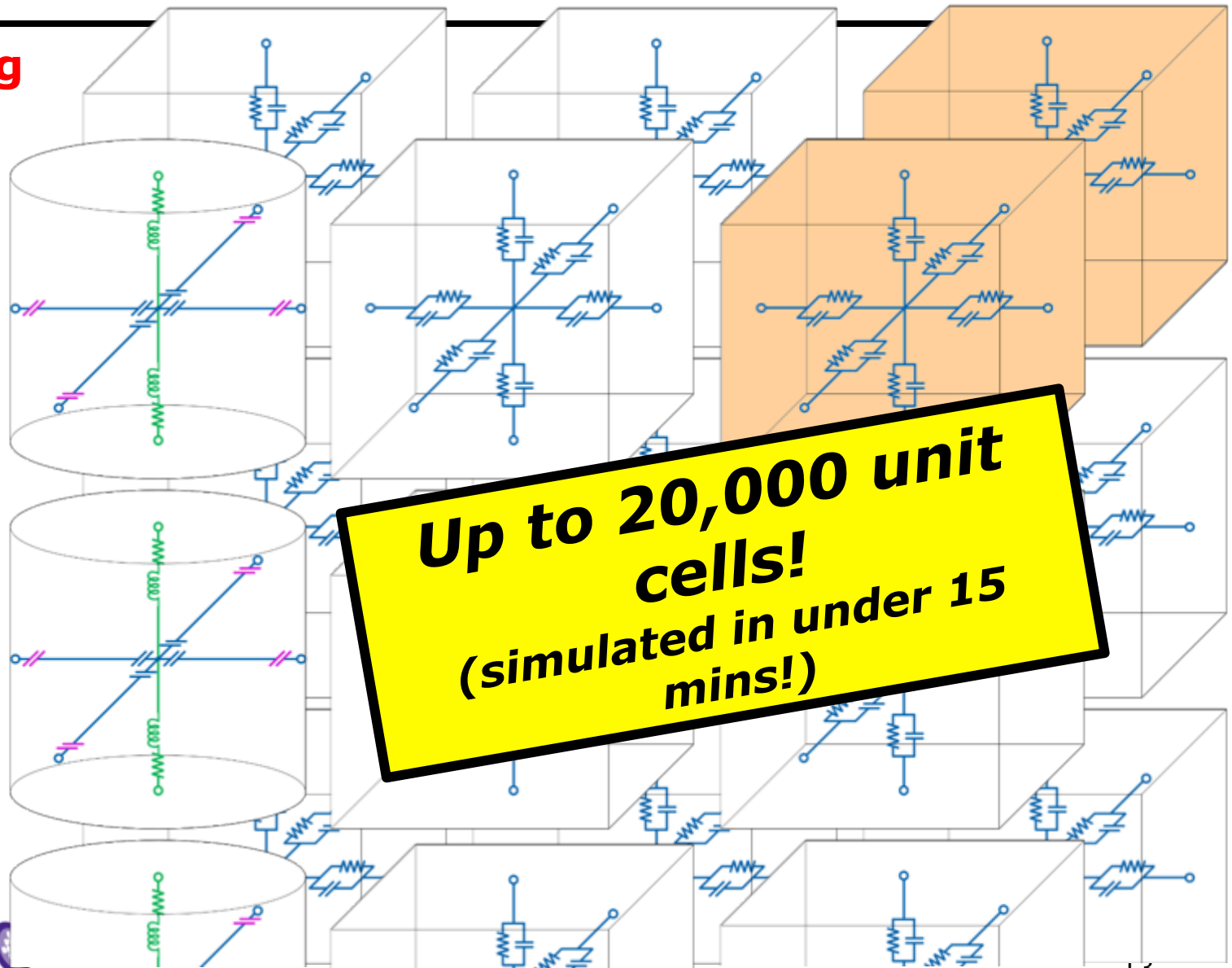


Substrate unit cell



FDM modeling example: **Coupling in 3DICs**

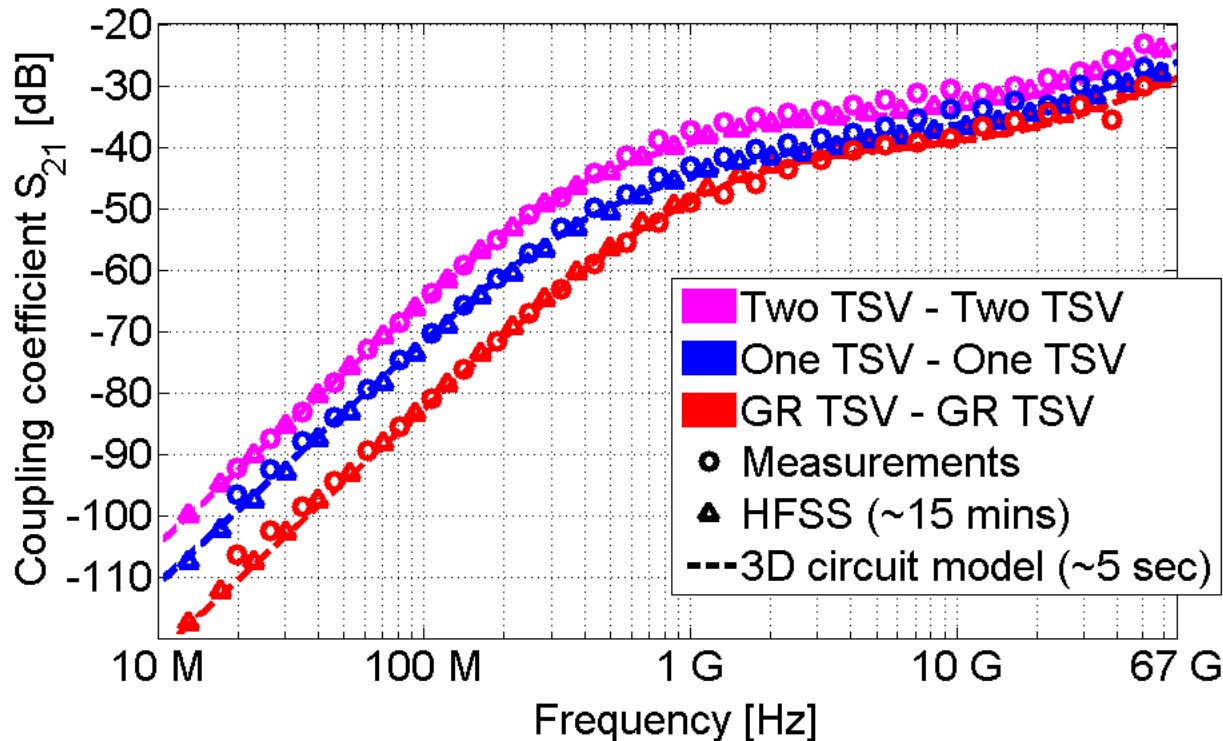
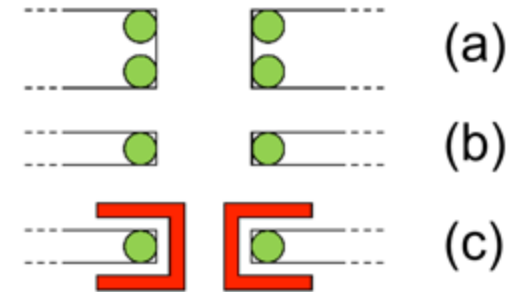
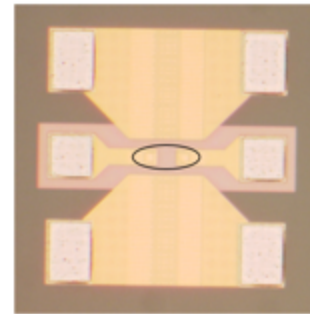
**Connecting
the cells:**



FDM modeling example: **Coupling in 3DICs**

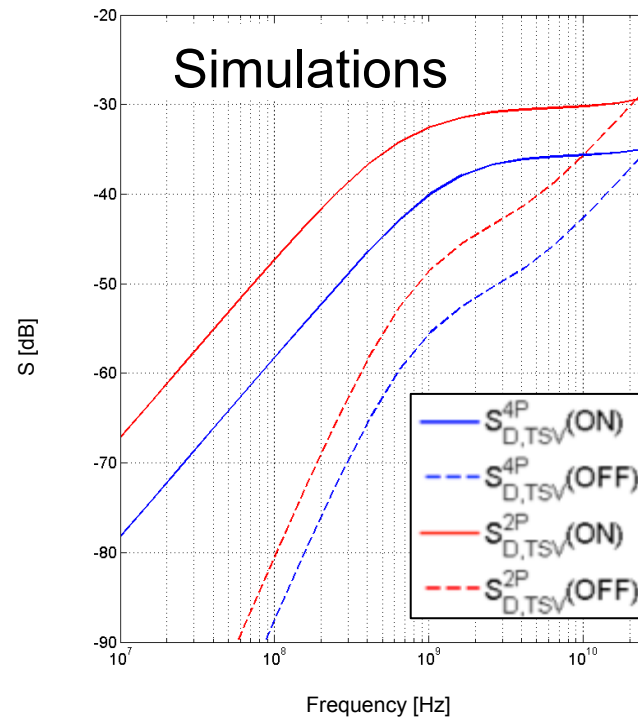
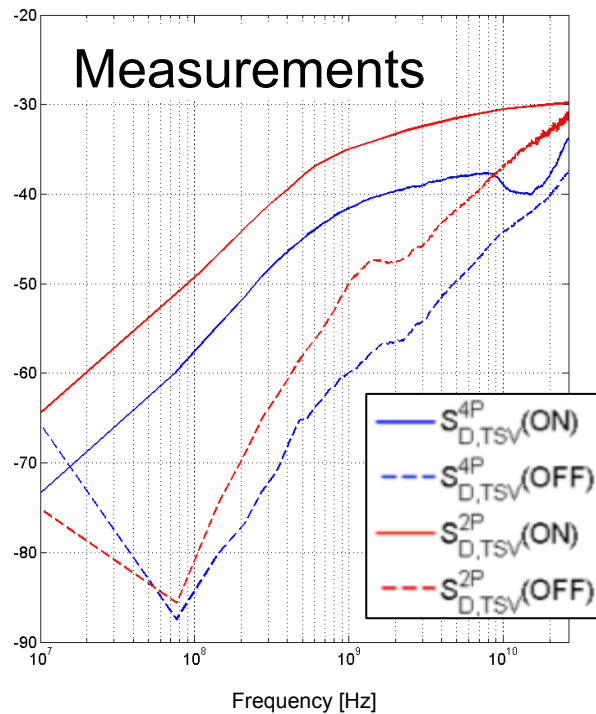
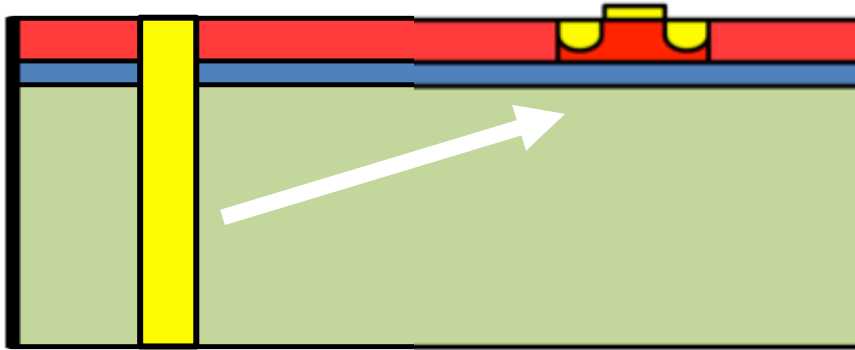
Three coupling test structures are considered to validate the model

- (a) Two TSV to Two TSV
- (b) One TSV to One TSV
- (c) GR TSV to GR TSV



- Agreement to both HFSS and RF measurements
- Complex field distributions are accurately modeled
- Much faster than HFSS: Maxwell $\rightarrow$ Kirchhoff
 $\Rightarrow$ Opens the door to larger, more complex simulations

FDM modeling example: **Coupling in 3DICs**



Non-linear substrate modeling

Motivation

Non-linearities distort signal

⇒ Information quality degraded

Origins?

Active devices

Passive devices ⇒ from substrate!

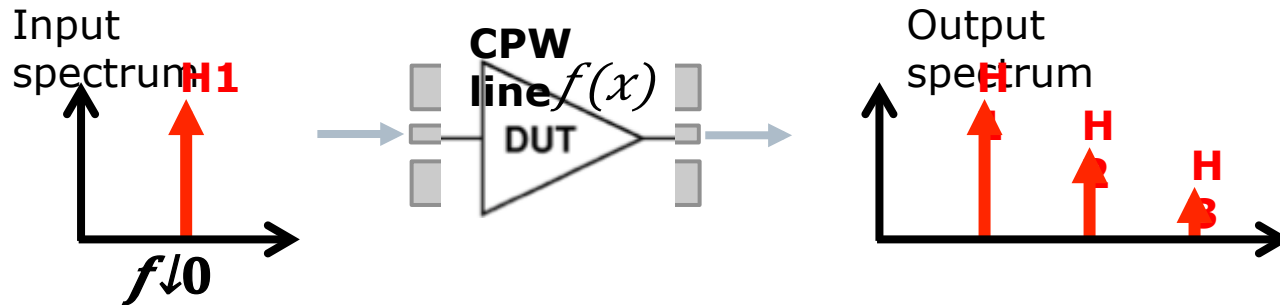
Example:

SOI RF switches

Non-linearity of interconnects dominate those of switch!

⇒ from substrate!

Non-linear signal distortion



Ideal transfer function:

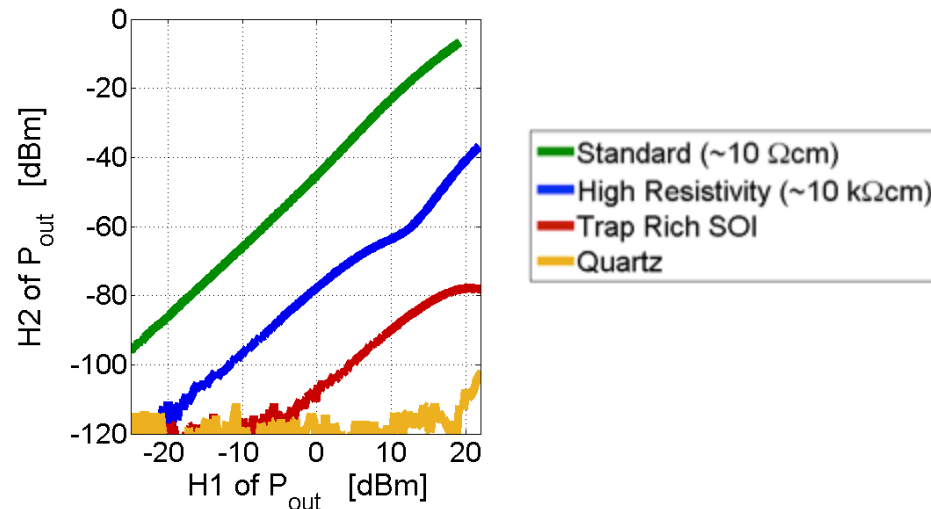
Actual transfer function:

...

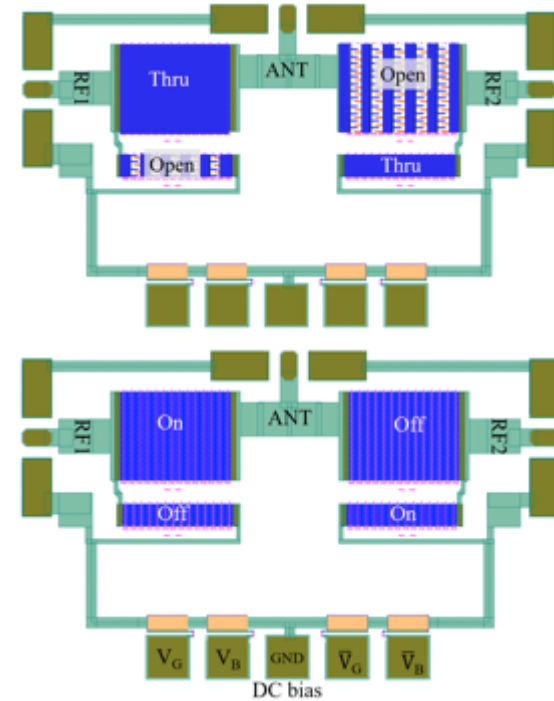
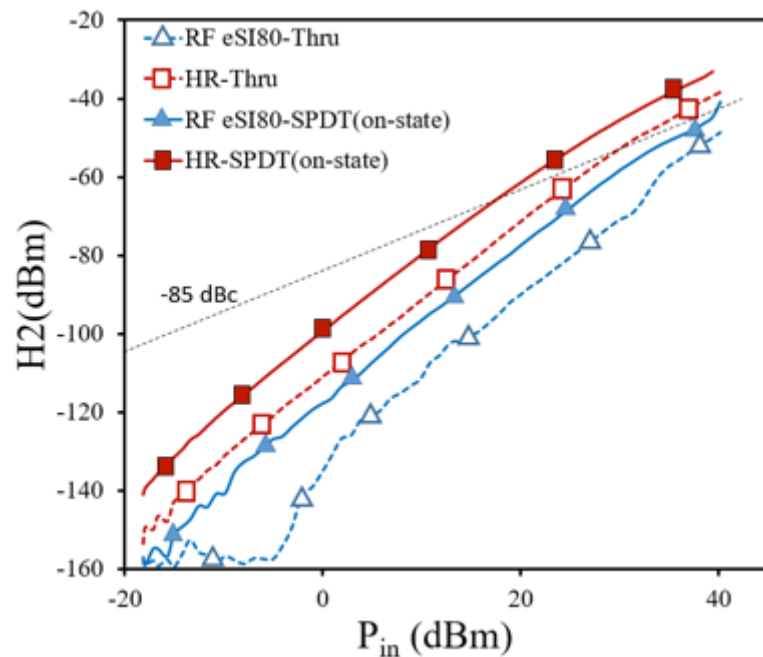
$$y = f(x) = a \cdot x$$

$$y = f(x) = a \cdot x + b \cdot x^2 + c \cdot x^3 + \dots$$

**900 MHz
fundamental
input**

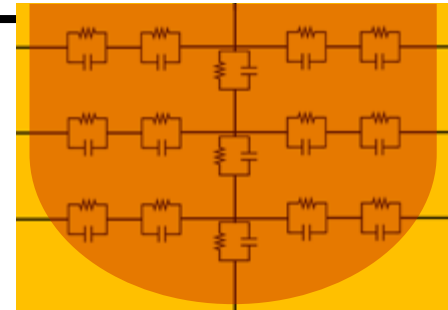


Example: RF switch

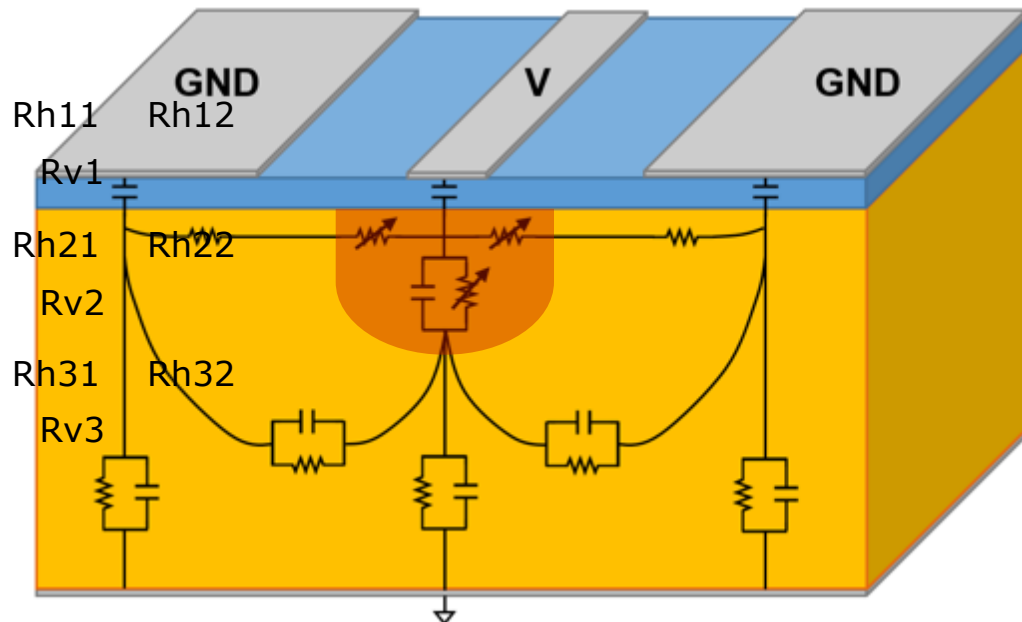


Modeling approach

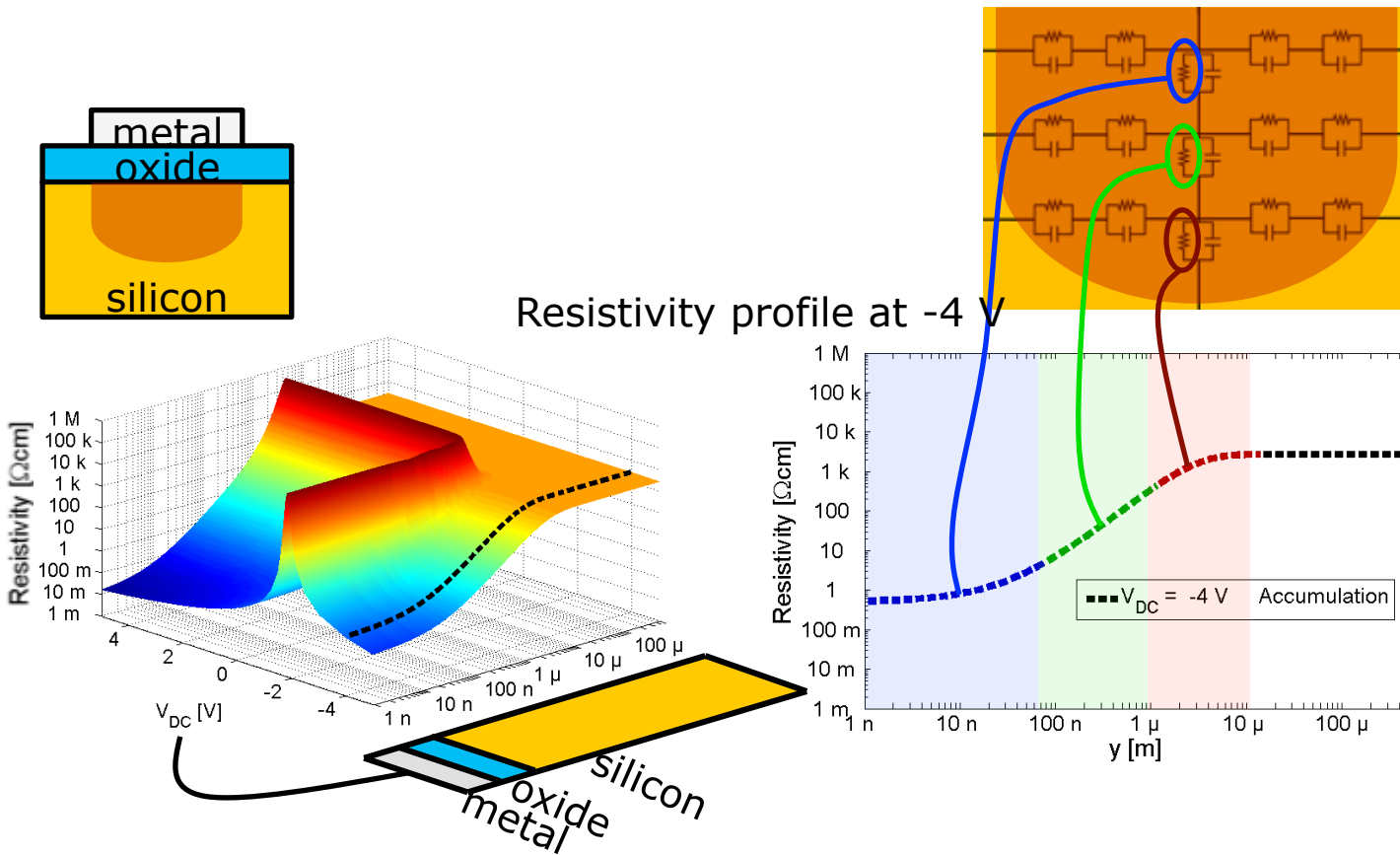
Semiconductors are non-linear by nature!
(Field effect)



**How to
model
 $R(V, t)$?**

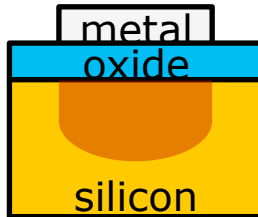


Modeling approach

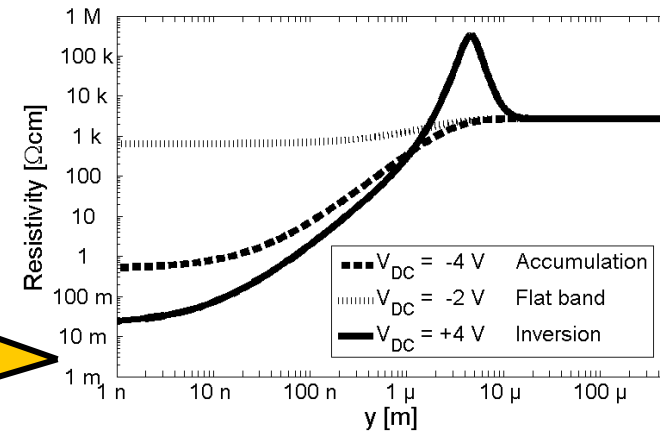
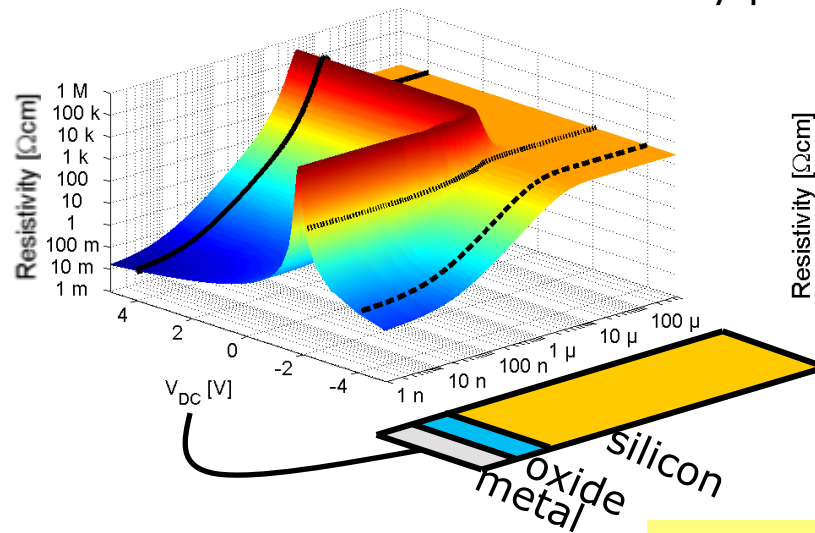
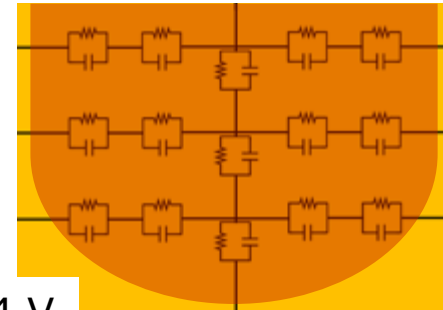


Integration $\int_a^b \dots dy \rightarrow$ Resistance values at -4 V

Modeling approach



Resistivity profile at +4 V

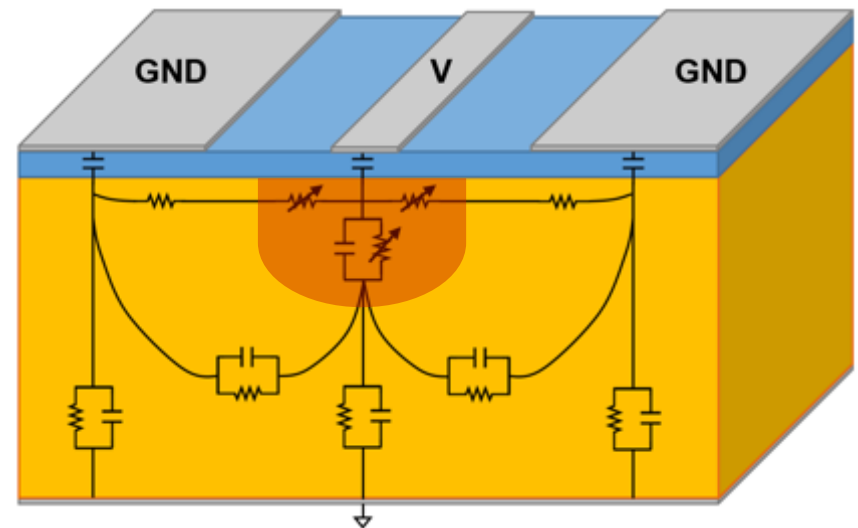
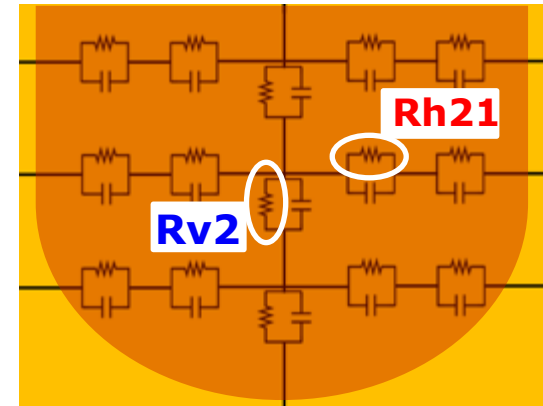
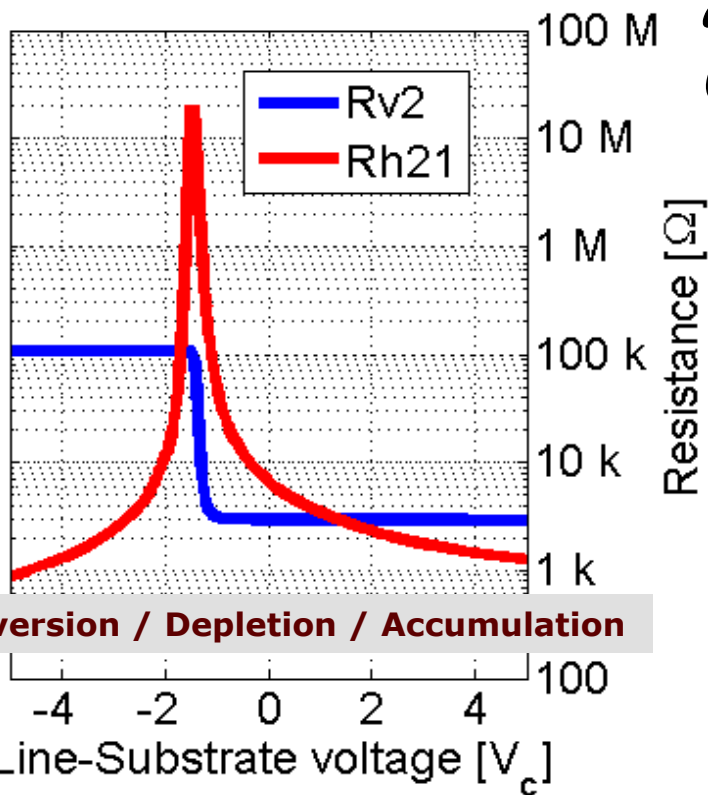


Integration of different curves at other voltages
→ Construct $R(V)$ relationship

Modeling approach

Construction of $R(V)$ **static** curves:

$R \uparrow St$
at
(V)



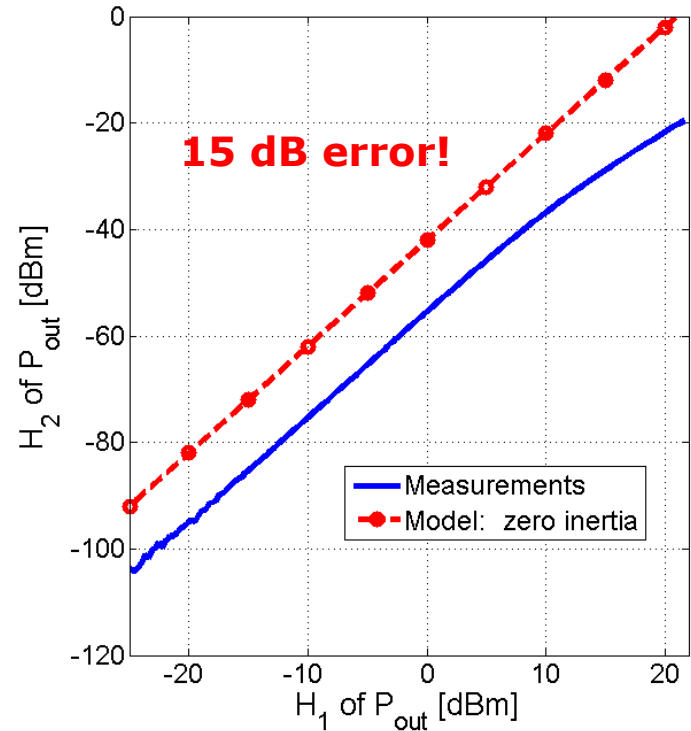
Finite inertia

Let's run our R(V) model...

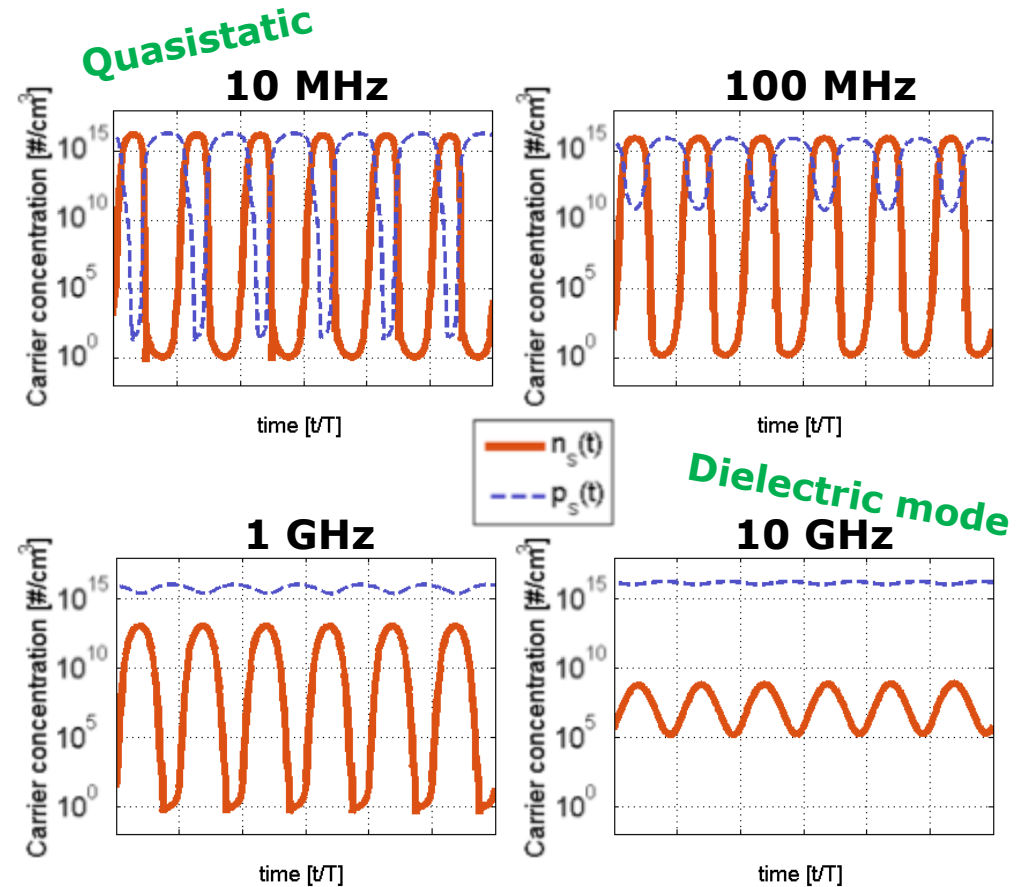
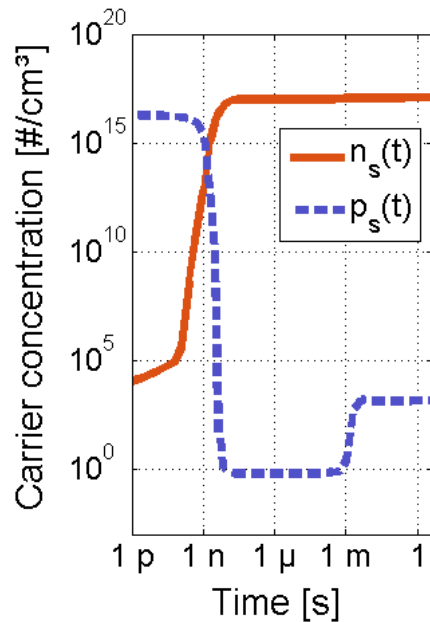
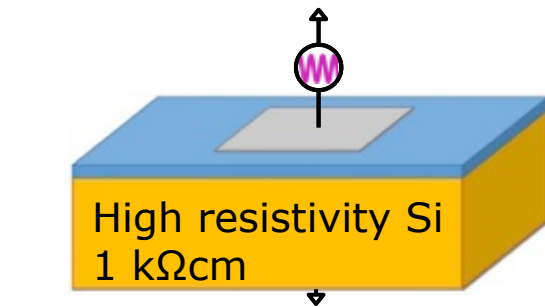
**Overestimation of
Harmonic
Distortion!**

Why?

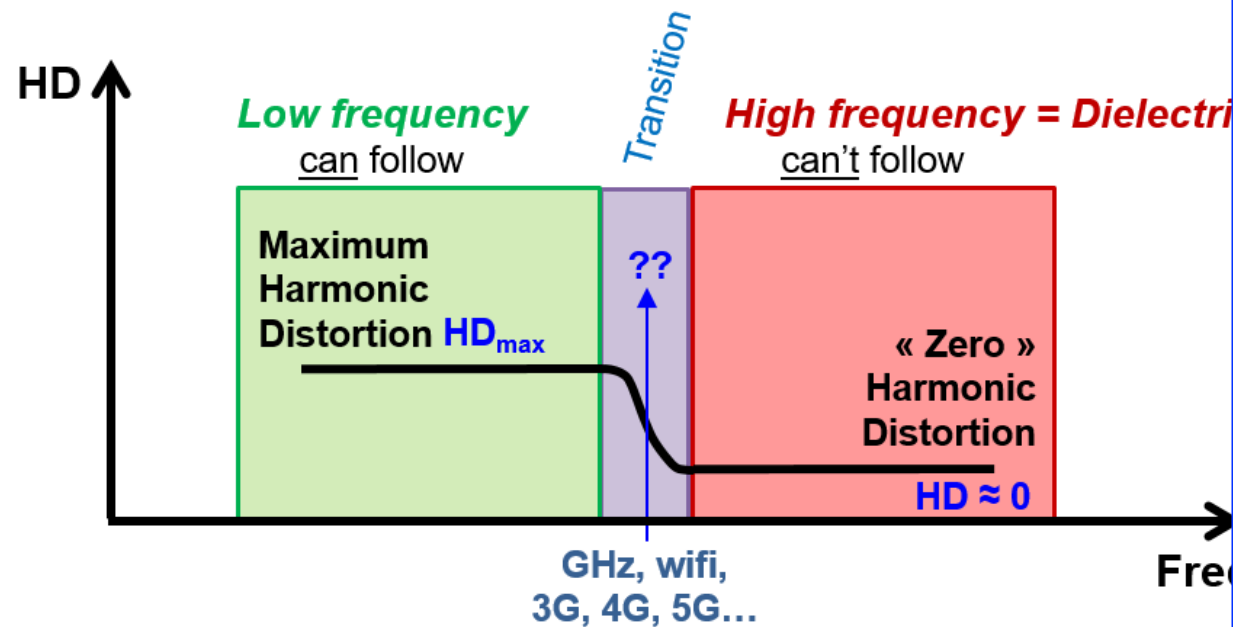
**At RF and mm-wave frequencies:
Carriers have some inertia, and
a certain finite response time!**



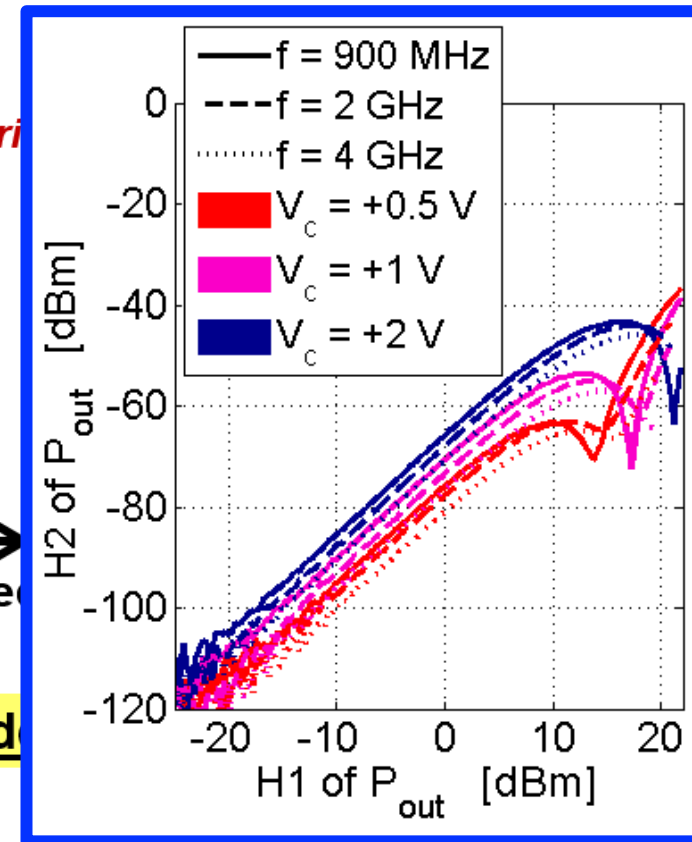
Carrier dynamics and finite inertia



Carrier dynamics and finite inertia



Partial following in the GHz band → model need



Carrier dynamics and finite inertia

When voltage goes from $V_{\downarrow i}$ to $V_{\downarrow i+1}$

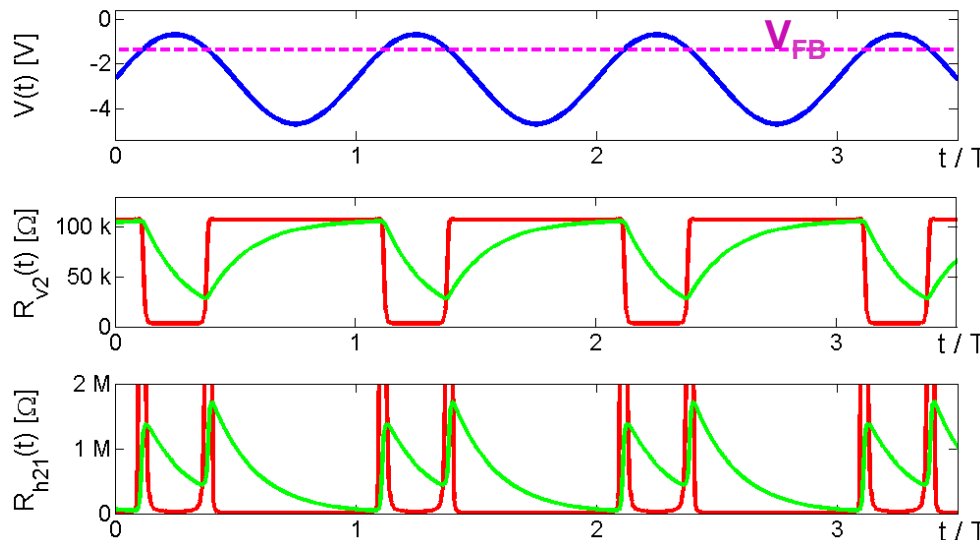
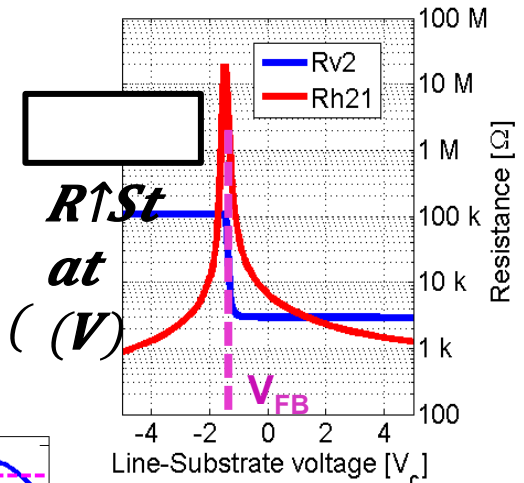
FDTD code

Zero inertia model:

$$R_{\downarrow i+1} = R_{\uparrow Stat}(V_{\downarrow i+1})$$

Finite inertia:

$$R_{\downarrow i+1} = R_{\uparrow Stat}(V_{\downarrow i+1}) - \exp(-\Delta t / \tau) \cdot (V)$$



$\tau \approx 0$
ns
 $\tau = 0.5$
ns

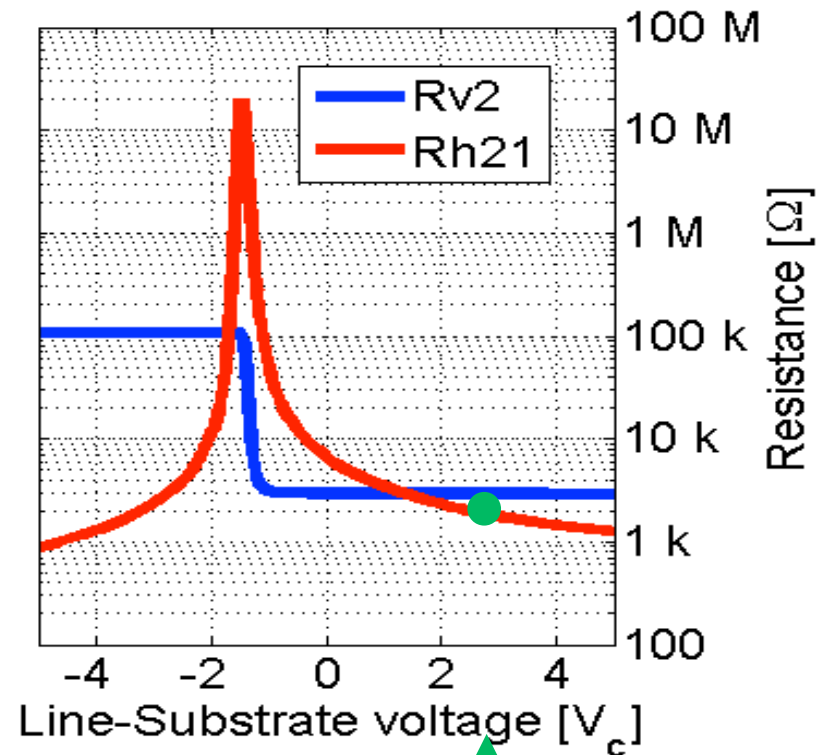
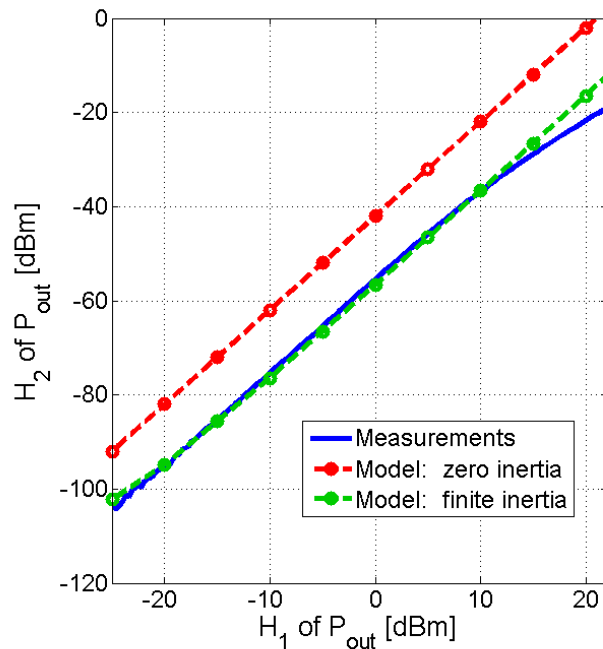
Has time to
follow $R(V(t))$
perfectly

Does not
have time to
follow
 $R(V(t))$
perfectly

Carrier dynamics and finite inertia

Introducing a time constant of $\tau=1.3$ ns

Simulations no longer overestimated

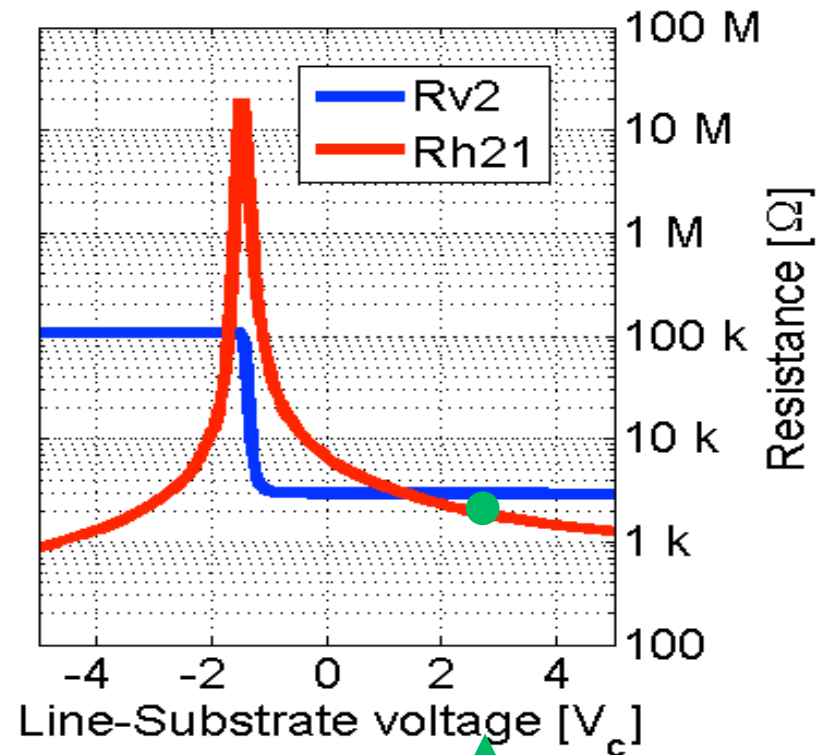
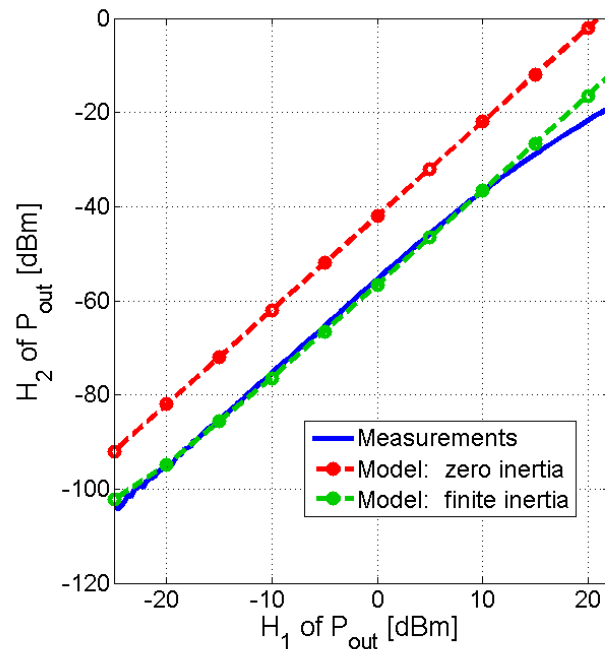


Zero carrier inertia

Carrier dynamics and finite inertia

Introducing a time constant of $\tau=1.3$ ns

Simulations no longer overestimated



Finite carrier inertia

Dips and saturations in HD components

A brief history of dips...

- Our industrial collaborators observed **dips in HD** ...but not very often...

- *Measurement error?*
- *Weird substrate?*

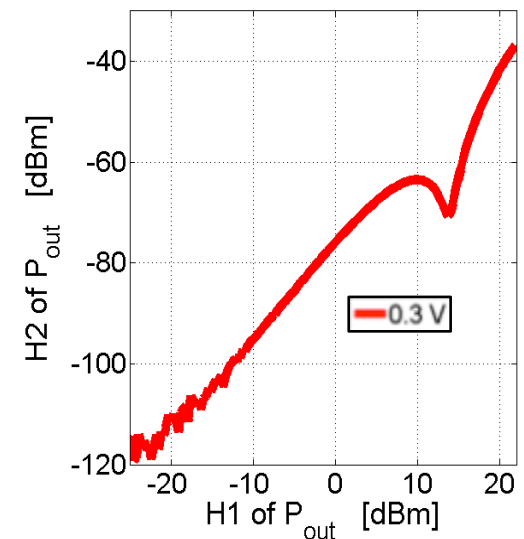
- Our research group was working on HD modeling, and we **had dips!** ...simulation tool from scratch...

- *Bad modeling?*
- *Coding bug?*

No error!

The modeling continued...

- investigate dips
- provide physical insight

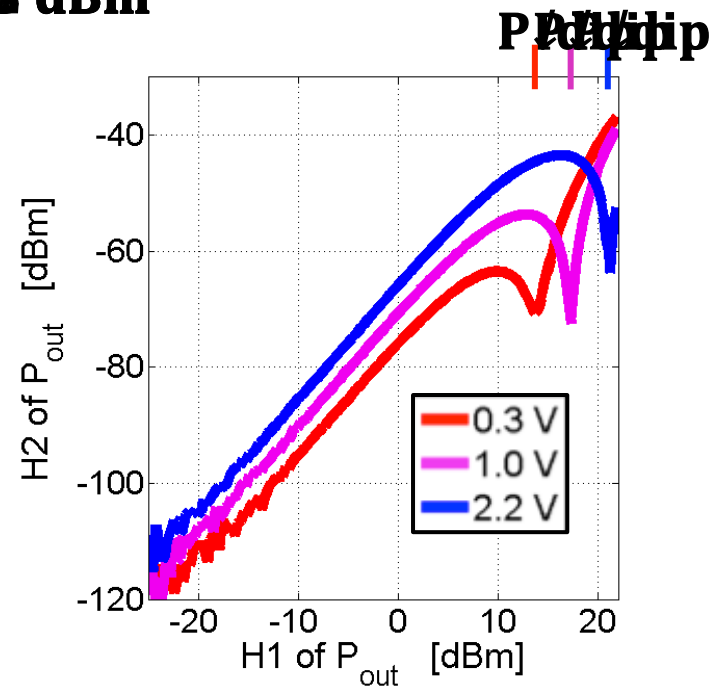
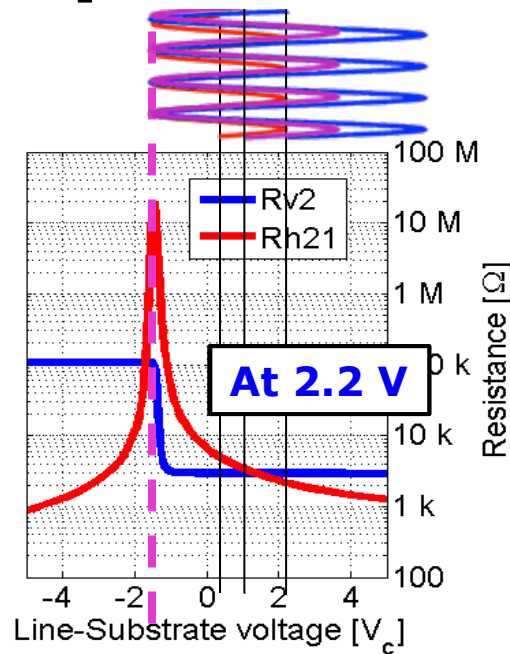


Dips and saturations in HD components

We see a dip when $|V_{DC} - V_{FB}| = A_{dip}$
monotonic point

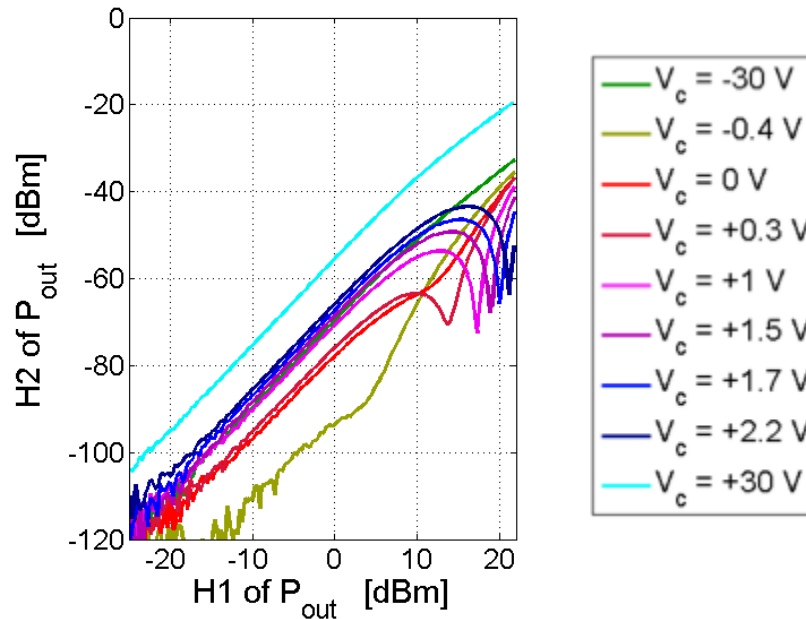
Non-

$$A_{dip} = 3.6 \text{ V} \leftrightarrow P_{dip} = 21.3 \text{ dBm}$$

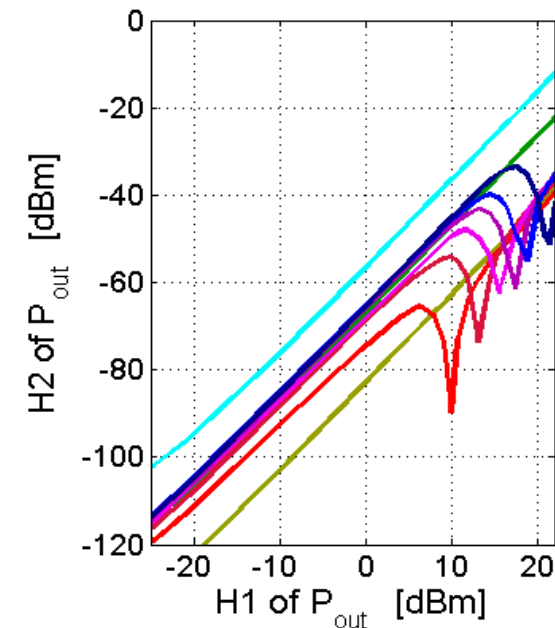


Dips and saturations in HD components

Measurements



Calibrated simulations



Good agreement can be achieved

Physical insight into origin of dips

Application

Tune position of dip with a DC bias

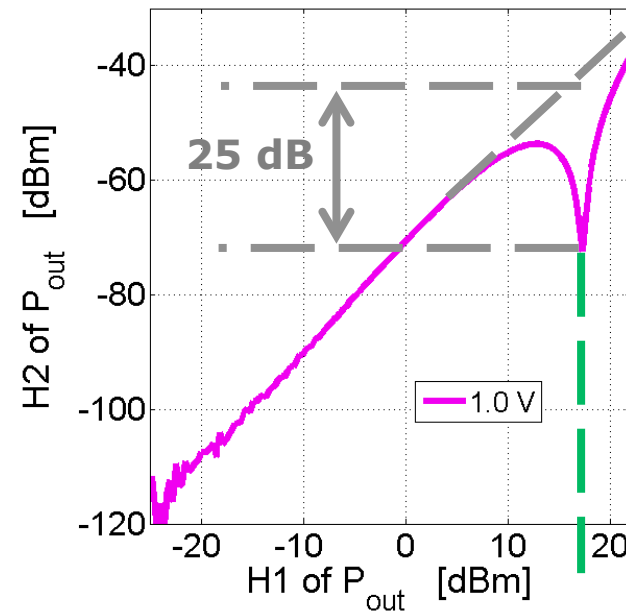
Say you have a circuit that runs **17 dBm** power.

⇒ You should bias DC at **+1.0 V** to be in the dip !

⇒ You gain 25 dB of linearity !

⇒ Possible to track the HD sweet spot with DC biasing

⇒ Patent submitted on this topic



Conclusions

- Electrical properties of substrate are of first importance
 - For small-signal crosstalk levels and RF losses
 - For large-signal distortion

- A variety of tools exist, for different purposes
 - Device physics / EM propagation / Lumped modeling
 - Non-linear substrate modeling is still in its early days...

- Novel modeling of substrate-induced Harmonic Distortion
 - Carrier dynamics taken into account for the first time
 - Dips in harmonic distortion curves
 - Insight into physical origin

Thanks for listening

Acknowledgements:

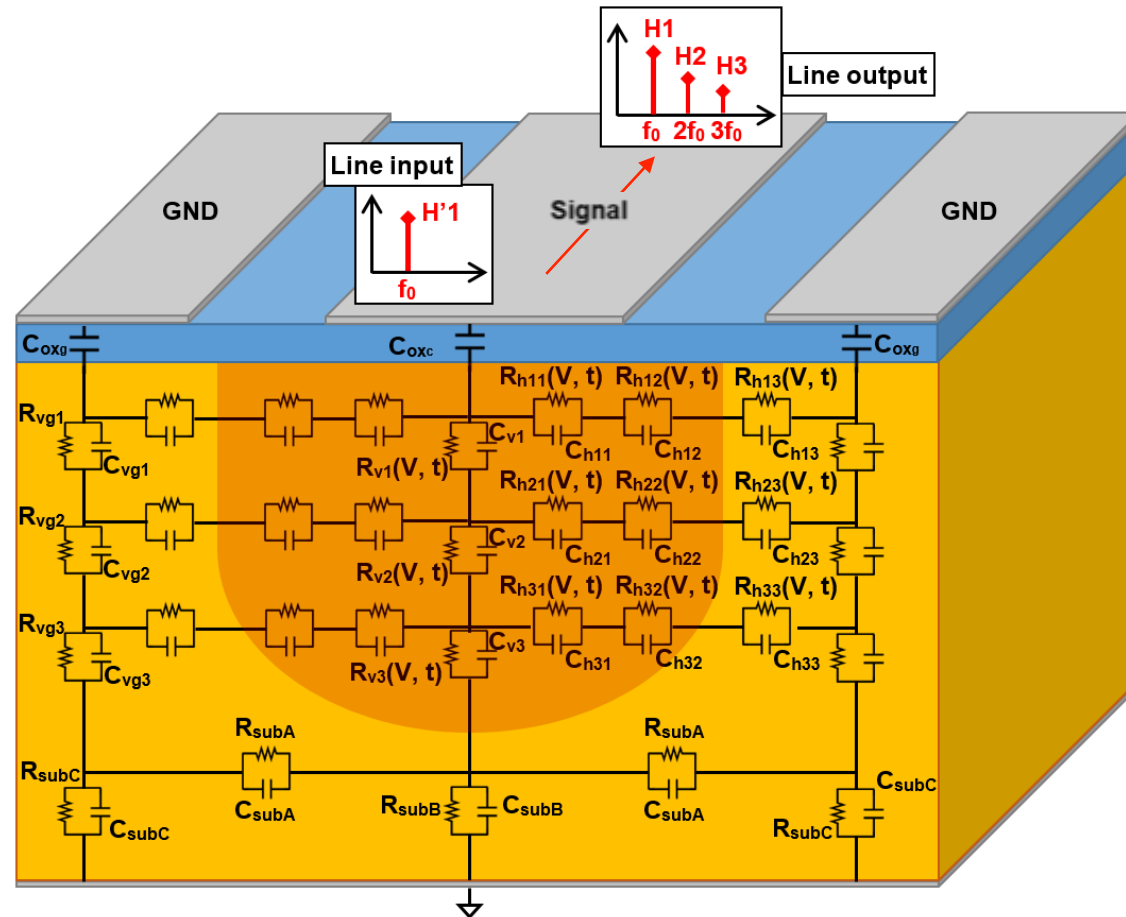
SOITEC, Incize, GlobalFoundries, CWS, TowerJazz
UCL's technological platforms Winfab and Welcome

TU2E-5

Backup slides

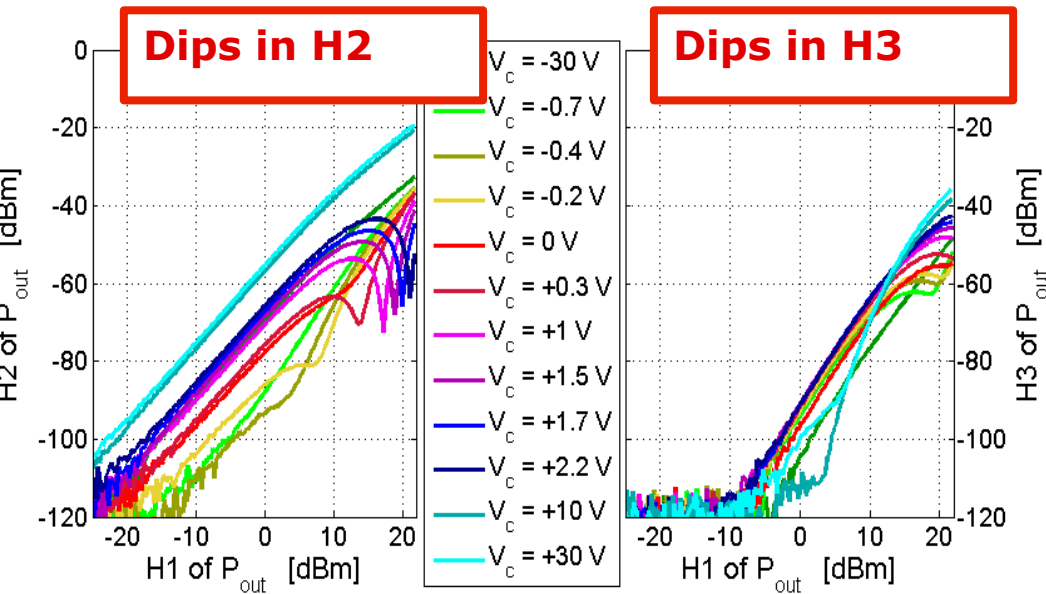
TU2E-5

Full model

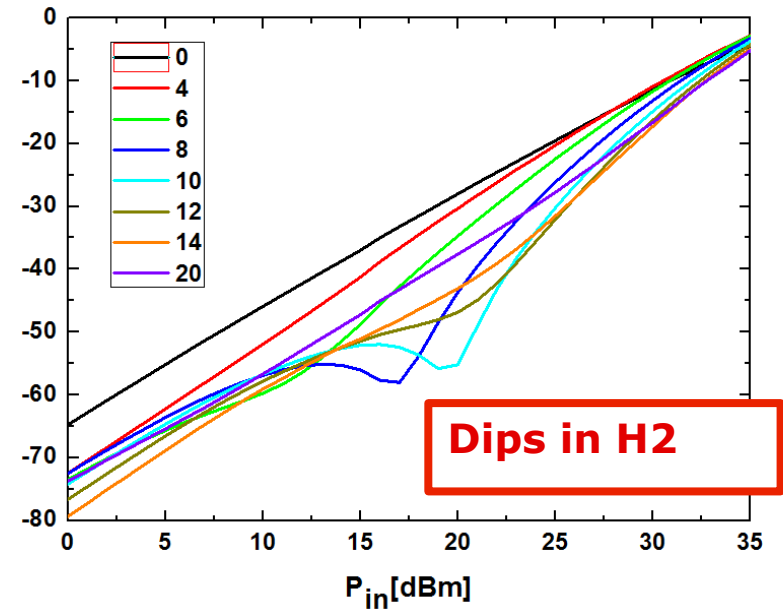


Dips on other substrates (1/3)

HR SOI (1)

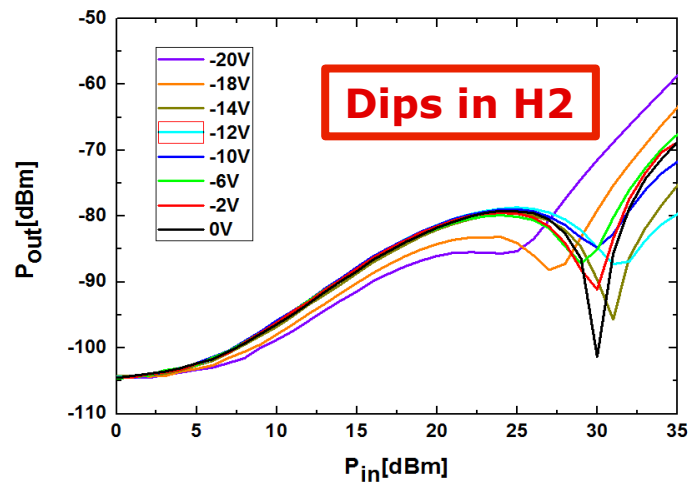


HR SOI (2)

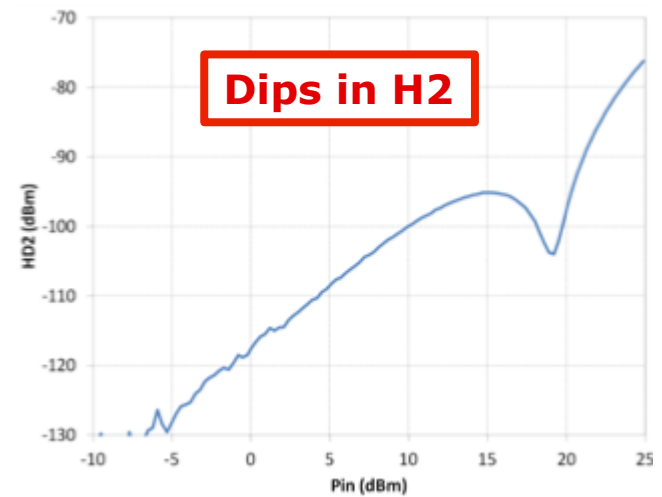


Dips on other substrates (2/3)

TR SOI (1)

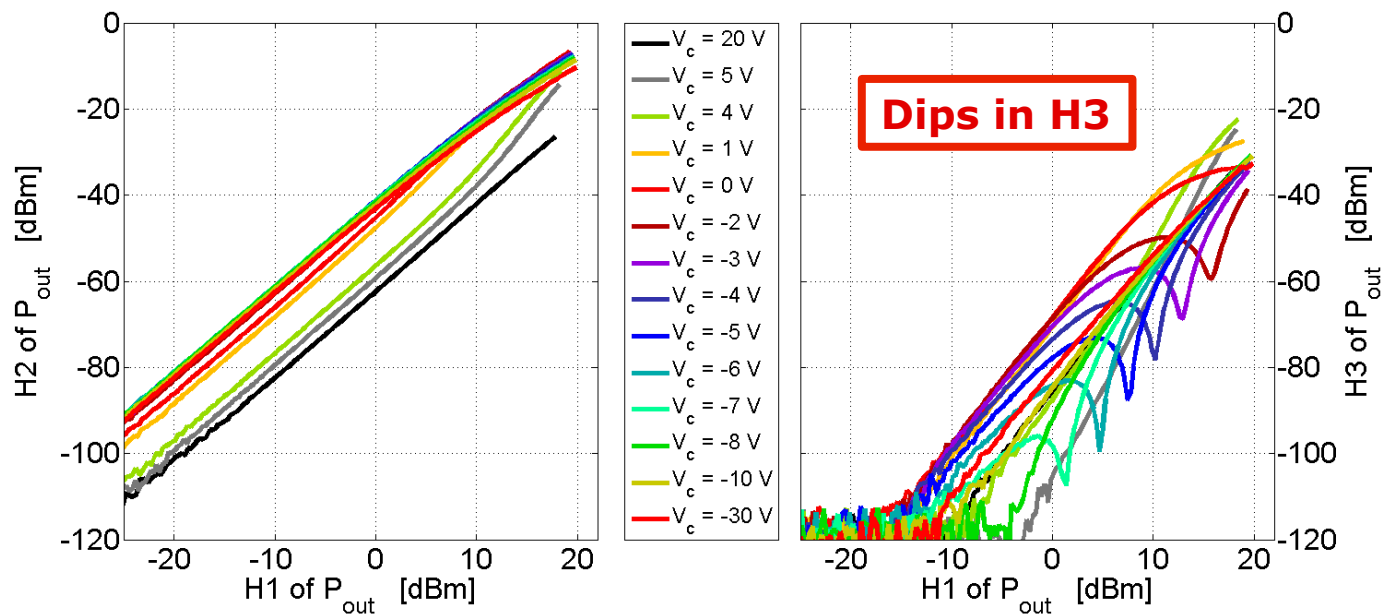


TR SOI (2)



Dips on other substrates (1/3)

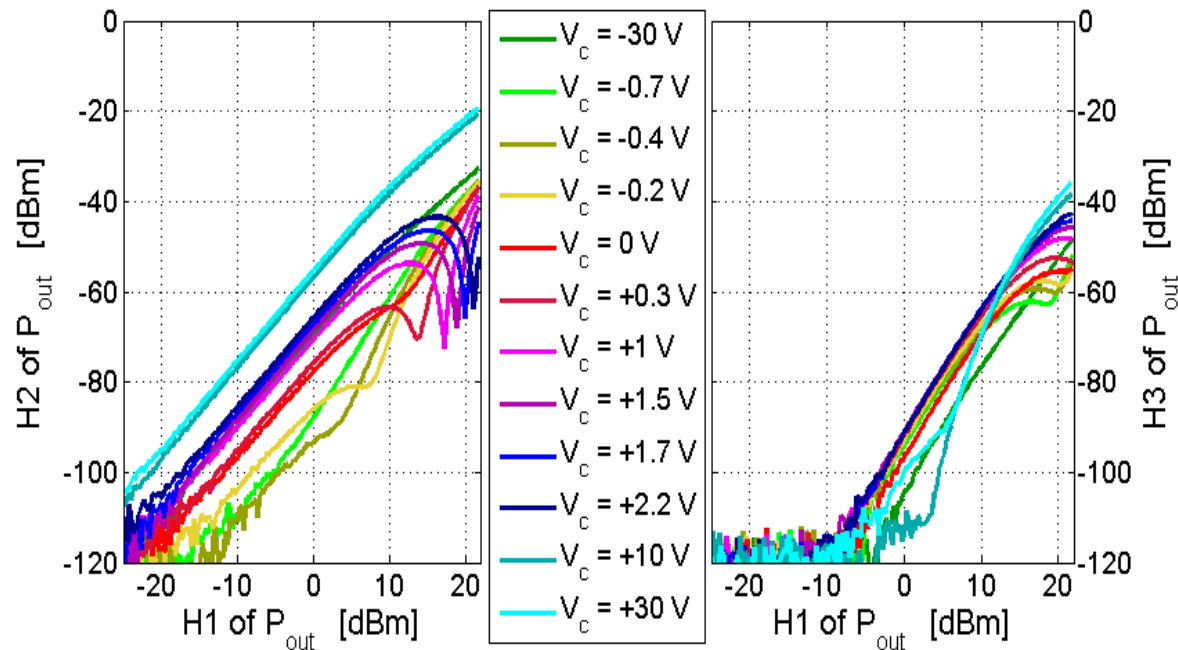
Standard resistivity



Dips are easy to miss!

⇒ See measurements below.

⇒ For a 25 dBm set up we only see the dips is we bias between +0.3 V and +5 V...



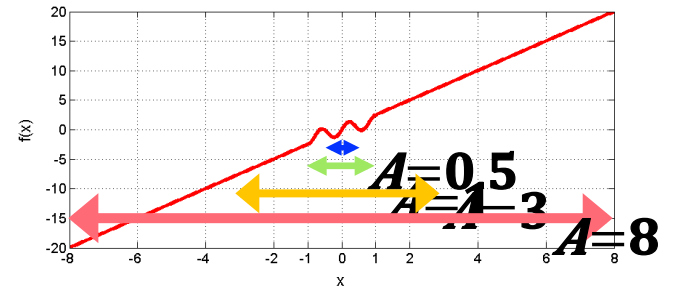
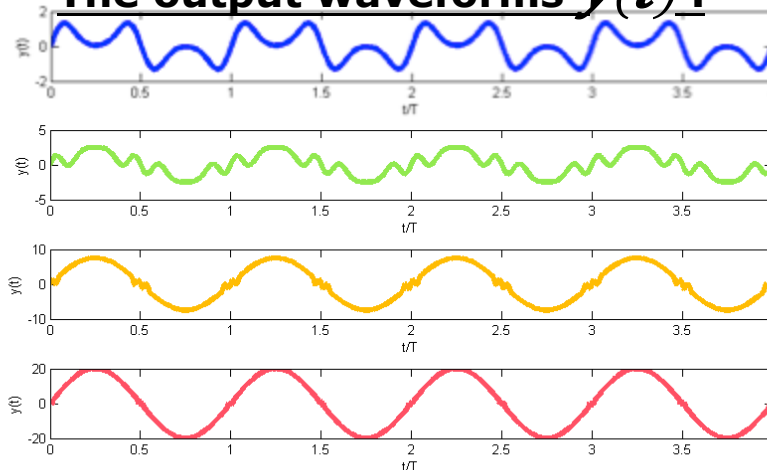
Dips and slopes, what does the math say??

We are used to transfer functions being “locally linear” as we zoom in.

⇒ Principle behind *small-signal analysis*

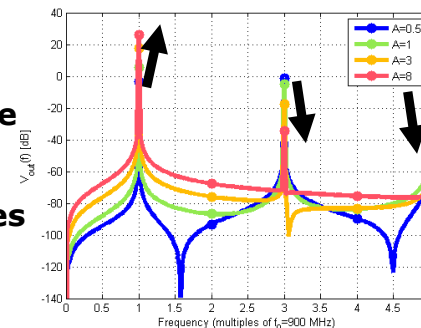
But actually, why not be more linear as we zoom out?

The output waveforms $y(t)$:



$f(x)$ totally linear between -8 and -1 and between +1 and +8
non-linear between -1 and +1

HD decrease
s as A
increases

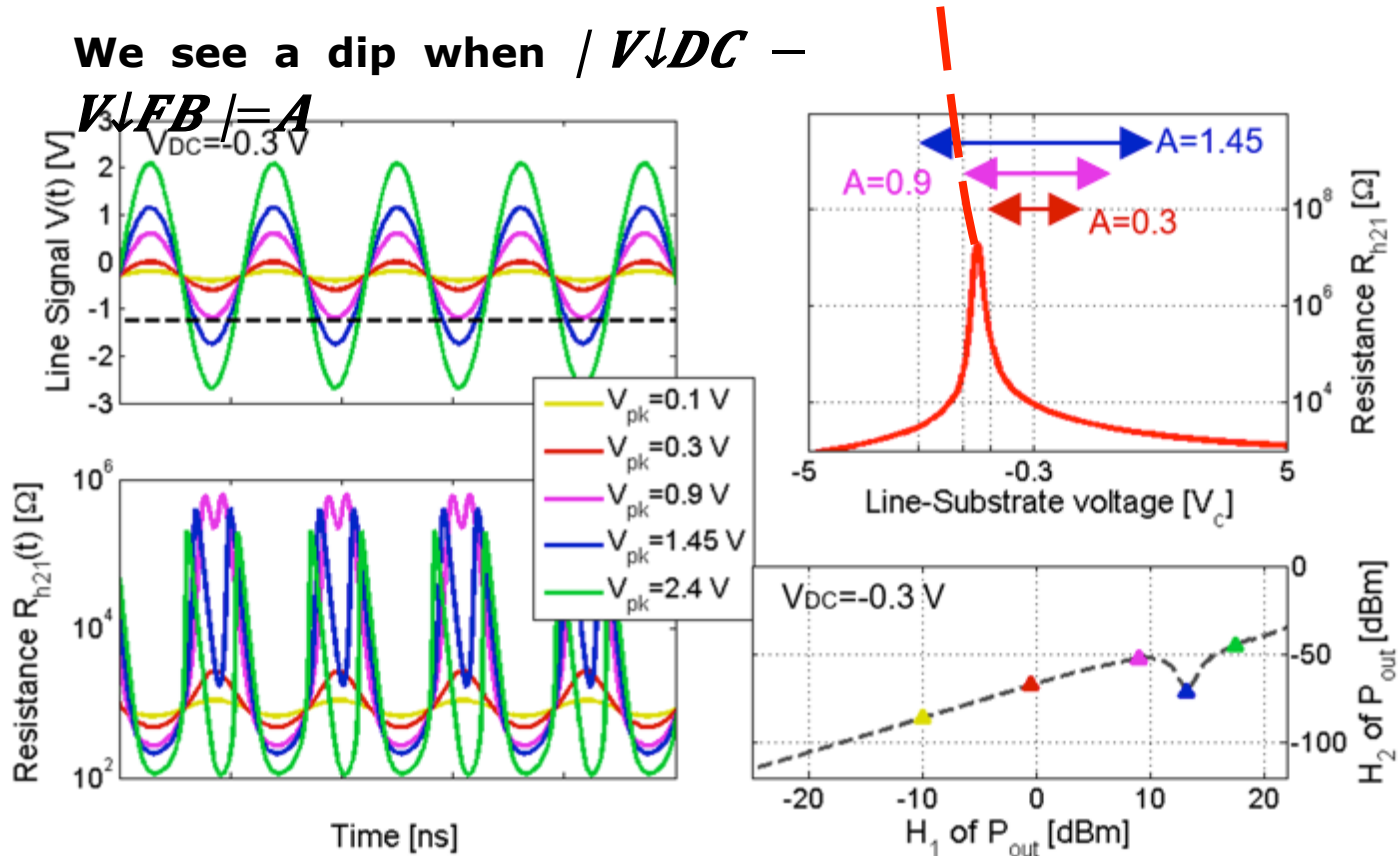


Going from small-signal to large signal results in a decrease of the HD!!
(= dip!)

Time domain resistance analysis (1/2)

We see a dip when $|V_{DC} -$

$V_{FB}| = A$



Time domain resistance analysis (2/2)

The analysis shows that when the RF voltage sweeps through the non-monotonic point, close to the flatband voltage, then the H2 components dips down (blue colored data in all figures).

When the resistance ceases to monotonically increase with the applied voltage, but suddenly decreases over the last part of the negative cycle of the large signal RF voltage wave, this resistance appears more linear because its direction of variation suddenly changes, instead of continuing along the same non-linear trend.